A tool for advanced learning of LFSR-based testing principles
Jutman, Artur; **Tšertov, Anton**; **Ubar, Raimund-Johannes** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 175-178 : ill

Aastad, mis möödusid linnulennul
Ubar, Raimund-Johannes Raimund-Johannes Ubar. Bibliograafia 2016 / lk. 13-44 : ill., fot

Abstraction of clock interface for conversion of RTL VHDL to SystemC
Saif Abrar, Syed; **Jenihhin, Maksim**; **Raik, Jaan** 2014 IEEE International Advance Computing Conference (IACC) : February 21-22, 2014, Gurgaon, India 2014 / p. 50-55 : ill

Accurate dialysis dose evaluation and extrapolation algorithms during online optical dialysis monitoring
Fridolin, Ivo; **Karai, Deniss**; **Kostin, Sergei**; **Ubar, Raimund-Johannes** IEEE transactions on biomedical engineering 2013 / p. 1371-1377 : ill https://doi.org/10.1109/TBME.2012.2234458 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Accurate NBTI-induced gate delay modeling based on intensive SPICE simulations
Kostin, Sergei; **Raik, Jaan**; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim** MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 21-26 : ill

Activity classification for real-time wearable systems : effect of window length, sampling frequency and number of features on classifier performance
Allik, Ardo; **Pilt, Kristjan**; **Karai, Deniss**; **Fridolin, Ivo**; **Leier, Mairo**; **Jervan, Gert** 2016 IEEE EMBS Conference on Biomedical Engineering and Sciences (IECBES) : Kuala Lumpur, 4-8 December 2016 2016 / p. 460-464 : ill
https://doi.org/10.1109/IECBES.2016.7843493

Address-based data processing over N-ary trees
Sklyarov, Valery; Skliarova, Iouliia; **Kruus, Margus**; **Mihhailov, Dmitri**; **Sudnitsõn, Aleksander** EuroCon 2013 : 01-04 July 2013, Zagreb, Croatia 2013 / p. 1790-1797 : ill

Advanced technical education in the age of cyber physical systems
Vierhaus, Heinrich Theodor; Schölzel, Mario; **Raik, Jaan**; **Ubar, Raimund-Johannes** 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 193-198 : ill

Advances in Databases and Information Systems : proceedings of the 9th East-European Conference, ADBIS 2005 : Tallinn, September 12-15, 2005
2005 https://www.ester.ee/record=b2068111*est

Akadeemilisest vabadusest ja riisiterast
Ubar, Raimund-Johannes Tallinna Tehnikaülikooli aastaraamat 2013 2014 / lk. 11-21

An ad-hoc implementation of a remote laboratory
Azad, Siavoosh Payandeh; **Kinks, Hannes**; **Tajammul, Muhammad Adeel**; **Ellervee, Peeter** 2015 International Conference on Microelectronic Systems Education : MSE '15 : Pittsburgh, PA, May 20-21, 2015 2015 / p. 48-51 : ill
http://dx.doi.org/10.1109/MSE.2015.7160015

An external test approach for network-on-a-chip switches
Raik, Jaan; **Govind, Vineeth**; **Ubar, Raimund-Johannes** ATS '06 : Proceedings of the 15th Asian Test Symposium : November 20-23, 2006, Fukuoka, Japan 2006 / p. 437-442 : ill http://dx.doi.org/10.1109/ATS.2006.23

Analysis and comparison of attainable hardware acceleration in all programmable systems-on-chip
Sklyarov, Valery; Skliarova, Iouliia; Silva, João; **Sudnitsõn, Aleksander** Euromicro Conference on Digital System Design : DSD 2015 : 26-28 August 2015, Funchal, Madeira, Portugal : proceedings 2015 / p. 345-352 : ill http://dx.doi.org/10.1109/DSD.2015.45

Applets for learning digital design and test [Electronic resource]
Ubar, Raimund-Johannes; **Jutman, Artur**; **Kruus, Margus**; Wuttke, Heinz-Dietrich 1st International Conference on Interactive Mobile and Computer Aided Learning (IMCL2006) : Amman, Jordan, April 19-21, 2006 2006 / p. 1-4 : ill. [CD-ROM]

Application of extensible processing platforms for experiments with FPGA-based circuits
Sklyarov, Valery; Skliarova, Iouliia; Silva, João; **Rjabov, Artjom**; **Sudnitsõn, Aleksander** MELECON 2014 : 2014 17th IEEE Mediterranean Electrotechnical Conference : 13-16 April 2014, Beirut, Lebanon 2014 / p. 467-471 : ill
https://doi.org/10.1109/MELCON.2014.6820579 Conference proceedings at Scopus Article at Scopus Article at WOS

Application of sequential test set compaction to LFSR reseeding
Aleksejev, Igor; **Jutman, Artur**; **Raik, Jaan**; **Ubar, Raimund-Johannes** 26th Norchip Conference : Tallinn, Estonia, 17-18

November 2008 : formal proceedings 2008 / p. 102-107 : ill http://dx.doi.org/10.1109/NORCHP.2008.4738292

Applying user domain model to improve Web recommendations
Robal, Tarmo; **Kalja, Ahto** Databases and information systems VII : selected papers from the tenth International Baltic Conference, DB&IS 2012 2013 / p. 118-131 https://doi.org/10.3233/978-1-61499-161-8-118 Conference Proceedings at Scopus Article at Scopus Article at WOS

APRICOT : a framework for teaching digital systems verification
Raik, Jaan; **Jenihhin, Maksim**; **Tšepurov, Anton**; **Reinsalu, Uljana**; **Ubar, Raimund-Johannes** 19th EAEEIE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 172-177 : ill http://dx.doi.org/10.1109/EAEEIE.2008.4610181

Arvutipõlvkonnad
Toomsalu, Arvo 2004 http://www.ester.ee/record=b1881924*est

Arvutitehnika riistvara : õpik kõrgkoolidele
Evartson, Teet 2013 https://www.ester.ee/record=b2967116*est

Assessment of diagnostic test for automated bug localization
Tihhomirov, Valentin; **Tšepurov, Anton**; **Jenihhin, Maksim**; **Raik, Jaan**; **Ubar, Raimund-Johannes** LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [6] p. : ill

Assessment of student's design results in e-learning-scenarios [Electronic resource]
Wuttke, Heinz-Dietrich; **Ubar, Raimund-Johannes**; Henke, Karsten; **Jutman, Artur** 8th International Conference on Technology Based Higher Education and Training : 10th to 13th July, 2007, KKR Hotel Kumamoto, Kumamoto, Japan : [proceedings] 2007 / [6] p. [CD-ROM]

Asutajadekaanid : eesmärk on anda inimestele võimalus oma tööd paremini teha
Oorn, Arvo; **Jervan, Gert**; **Kanger, Tõnis**; **Listra, Enn** Mente et Manu 2016 / lk. 18-23 : fot https://artiklid.elnet.ee/record=b2797132*est

Asynchronous fault detection in IEEE P1687 instrument network
Shibin, Konstantin; **Devadze, Sergei**; **Jutman, Artur** IEEE 23rd North Atlantic Test Workshop : 14-16 May 2014, Binghampton, New York : proceedings 2014 / p. 73-78 : ill

At-speed functional built-in self-test methodology for processors [Electronic resource]
Ubar, Raimund-Johannes; **Indus, Viljar**; **Kalmend, Oliver** Proceedings of the IASTED International Conference on Engineering and Applied Science : December 27-29, 2012, Columbo, Sri Lanka 2012 / p. 168-172 : ill [CD-ROM]

At-speed self-testing of high-performance pipe-lined processing architectures [Electronic resource]
Gorev, Maksim; **Ubar, Raimund-Johannes**; **Ellervee, Peeter**; **Devadze, Sergei**; **Raik, Jaan**; **Min, Mart** 31st Norchip Conference : Vilnius, Lithuania, 11-12 November 2013 : conference program and papers 2013 / p. 1-6 : ill [USB]

At-speed testing and test quality evaluation for high-performance pipelined systems Töökiirusel testimine ja testi kvaliteedi hindamine kõrgjõudlus-konveierarhitektuuriga süsteemidele
Gorev, Maksim 2015 https://digi.lib.ttu.ee/i/?3953

At-speed testing of inter-die connections of 3D-SICs in the presence of shore logic
Shibin, Konstantin; Chickermane, Vivek; Keller, Brion; Papameletis, Christos; Marinissen, Erik Jan 2015 Asian Test Symposium : ATS 2015 : 22-25 November 2015, Mumbai, Maharashtra, India : proceedings 2015 / p. 79-84 : ill https://doi.org/10.1109/ATS.2015.21 Conference proceedings at Scopus Article at Scopus Article at WOS

Aukartus teaduse ees
Ubar, Raimund-Johannes Raimund-Johannes Ubar. Bibliograafia 2016 / lk. 47-56

Aukartus teaduse ees : [essee]. Nikolai Alumäe medal
Ubar, Raimund-Johannes Sirp 2014 / lk. 3-5 : fot https://www.sirp.ee/s1-artiklid/c21-teadus/aukartus-teaduse-ees/

Automated design error debug using high-level decision diagrams and mutation operators
Raik, Jaan; **Repinski, Urmas**; **Tšepurov, Anton**; **Hantson, Hanno**; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim** Microprocessors and microsystems 2013 / p. 505-513 : ill https://doi.org/10.1016/j.micpro.2012.11.004 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Automated design error localization in RTL designs
Jenihhin, Maksim; **Tšepurov, Anton**; **Tihhomirov, Valentin**; **Raik, Jaan**; **Hantson, Hanno**; **Ubar, Raimund-Johannes**; Bartsch, Günter; Meza Escobar, Jorge Hernan; Wuttke, Heinz-Dietrich IEEE design & test of computers 2014 / p. 83-92 : ill

https://doi.org/10.1109/MDAT.2013.2271420 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Automated minimization of concurrent online checkers for network-on-chips
Saltarelli, Pietro; **Niazmand, Behrad**; **Hariharan, Ranganathan**; **Raik, Jaan**; **Jervan, Gert**; **Hollstein, Thomas** 10th International Symposium on Reconfigurable and Communication-centric Systems-on-Chip (ReCoSoC 2015) : Bremen, 29 June - 1 July 2015 2015 / [8] p. : ill http://dx.doi.org/10.1109/ReCoSoC.2015.7238079

Automatic distribution of local testers for testing distributed systems
Vain, Jüri; **Halling, Evelin**; **Kanter, Gert**; **Anier, Aivo**; **Pal, Deepak** Databases and information systems IX : selected papers from the twelfth International Baltic Conference, DB&IS 2016 2016 / p. 297-310 : ill https://doi.org/10.3233/978-1-61499-714-6-297 Conference Proceedings at Scopus Article at Scopus Article at WOS

BASTION - board and SoC test instrumentation for Ageing and No Failure Found
Devadze, Sergei MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 77

BIST analyzer : a training platform for SoC testing [Electronic resource]
Jutman, Artur; **Tšertov, Anton**; **Tšepurov, Anton**; **Aleksejev, Igor**; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich 37th Annual Frontiers in Education Conference : Global Engineering : Knowledge Without Borders, Opportunities Without Passports : Milwaukee, Wisconsin, October 10-13, 2007 2007 / p. S3H-8-S3H-13 : ill. [CD-ROM] http://dx.doi.org/10.1109/FIE.2007.4418125

Boolean fault dignosis with structurally synthesized BDDs
Ubar, Raimund-Johannes Recent progress in the Boolean domain 2014 / p. 303-331 : ill

Bringing research issues into lab scenarios on the example of SoC testing [Electronic resource]
Ubar, Raimund-Johannes; **Jutman, Artur**; **Devadze, Sergei**; Wuttke, Heinz-Dietrich International Conference on Engineering Education - ICEE 2007 : September 3-7, 2007, Coimbra, Portugal 2007 / [7] p. : ill. [CD-ROM] http://icee2007.dei.uc.pt/proceedings/papers/429.pdf

Clock manipulation for heterogeneous emulation environment
Ellervee, Peeter; Arhipov, Anton; **Tammemäe, Kalle** Proceedings [of] 24th IEEE Norchip Conference : Linköping, Sweden, 20-21 November 2006 2006 / p. 213-216 : ill https://ieeexplore.ieee.org/abstract/document/4126984

CMS drift tubes sector collector relocation phase 1 upgrade [Electronic resource]
Bedoya, C. F.; **Jutman, Artur**; **Shibin, Konstantin**; **Devadze, Sergei** 2015 http://cms.cern.ch/iCMS/jsp/openfile.jsp?type=DN&year=2015&files=DN2015_011.pdf

Code compaction within CGRAs
Tajammul, Muhammad Adeel; Jafri, Syed Mohammad Asad Hassan; **Ellervee, Peeter** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 133-136 : ill

Code coverage analysis for concurrent programming languages using high-level decision diagrams
Jenihhin, Maksim; **Raik, Jaan**; **Tšepurov, Anton**; **Reinsalu, Uljana**; **Ubar, Raimund-Johannes** Proceedings of the 12th European Workshop on Dependable Computing : EWDC 2009 : Toulouse, France, May 14-15, 2009 2009 / [4] p. : ill https://hal.archives-ouvertes.fr/hal-00381559

Combinational fault simulation in sequential circuits
Ubar, Raimund-Johannes; **Kõusaar, Jaak**; **Gorev, Maksim**; **Devadze, Sergei** 2015 IEEE International Symposium on Circuits and Systems : 24-27 May 2015, Lisboa, Portugal : [proceedings] 2015 / p. 2876-2879 : ill https://doi.org/10.1109/ISCAS.2015.7169287 Conference proceedings at Scopus Article at Scopus Article at WOS

Combinatorial algorithms of discrete mathematics
Zakrevskij, Arkadij; Pottosin, Yu.; Cheremisinova, L. 2008 http://www.ester.ee/record=b2350865*est

Combining learning, training and research in laboratory course for design and test
Ubar, Raimund-Johannes; **Orasson, Elmet**; **Raik, Jaan**; Wuttke, Heinz-Dietrich The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 221-224 : ill https://www.researchgate.net/publication/242397131_Combining_Learning_Training_and_Research_in_Laboratory_Course_for_Design_and_Test

Comparative analysis of sequential circuit test generation approaches
Raik, Jaan; Krivenko, Anna; **Ubar, Raimund-Johannes** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 225-228 : ill

Comparison of plan-driven and agile project management approaches : theoretical bases for a case study in Estonian

software industry
Lepmets, Marion; **Nael, Margus** Databases and Information Systems VI : selected papers from the Ninth International Baltic Conference, DB&IS 2010 2011 / p. 296-308 : ill

Comparison of two approaches to improve functional BIST fault coverage
Kostin, Sergei; **Ubar, Raimund-Johannes**; **Gorev, Maksim**; **Mägi, Gunnar** BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 105-108 : ill

Complementing ICT studies with learning objects on domain ontologies
Robal, Tarmo; **Kruus, Helena**; **Kalja, Ahto** Proceedings of the 24th International Conference on European Association for Education in Electrical and Information Engineering : 30-31 May 2013, Chania, Greece 2013 / p. 92-96 : ill

Complex delay fault reasoning with sequential 7-valued algebra
Kõusaar, Jaak; **Ubar, Raimund-Johannes**; **Aleksejev, Igor** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill http://dx.doi.org/10.1109/LATW.2015.7102403

Comprehensive abstraction of VHDL RTL cores to ESL SystemC = Register-siirde taseme VHDL kirjelduste kompleksne abstraheerimine süsteemitaseme SystemC mudeliteks
Abrar, Syed Saif 2016 http://www.ester.ee/record=b4564850*est

Computing sorted subsets for data processing in communicating software/hardware control systems
Sklyarov, Valery; Skliarova, Iouliia; **Rjabov, Artjom**; **Sudnitsõn, Aleksander** International journal of computers communications & control 2016 / p. 126-141 : ill https://doi.org/10.15837/ijccc.2016.1.1442 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Constraints solving based hierarchical test generation for synchronous sequential circuits = Kitsenduste lahendamisel baseeruv hierarhiline testigenereerimine sünkroonsetele järjestikskeemidele
Viilukas, Taavi 2012 https://www.ester.ee/record=b2888278*est

Construction of the tests of combinational circuit failures by analyzing the orthogonal disjunctive normal forms represented by the alternative graphs
Matrosova, A.Yu.; Pleshkov, A.G.; **Ubar, Raimund-Johannes** Automation and remote control 2005 / p. 313-327 : ill https://doi.org/10.1007/s10513-005-0054-9

Control intensive digital system synthesis
Tammemäe, Kalle 1997 http://www.ester.ee/record=b1060033*est

Critical path tracing based simulation of transition delay faults
Kõusaar, Jaak; **Ubar, Raimund-Johannes**; **Devadze, Sergei**; **Raik, Jaan** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 61-66 : ill

Critical path tracing based simulation of transition delay faults
Kõusaar, Jaak; **Ubar, Raimund-Johannes**; **Devadze, Sergei**; **Raik, Jaan** 2014 17th Euromicro Conference on Digital System Design : DSD 2014 : 27-29 August 2014, Verona, Italy : proceedings 2014 / p. 108-113 : ill

Customizable compression architecture for efficient configuration in CGRAs
Jafri, Syed Mohammad Asad Hassan; **Ellervee, Peeter** 2014 IEEE 22nd International Symposium on Field-Programmable Custom Computing Machines : FCCM 2014 : 11-13 May 2014, Boston, Massachusetts, USA : proceedings 2014 / p. 31 : ill

Customization methodology of a Coarse Grained Reconfigurable Architecture
Azad, Siavoosh Payandeh; Farahini, Nasim; Hemani, Ahmed Norchip : 32nd NORCHIP Conference, 27-28 October 2014, Tampere, Finland 2014 / [4] p. : ill

Data type dependent energy consumption estimation
Ruberg, Priit; **Lass, Keijo**; **Ellervee, Peeter** 2nd IEEE NORCAS Conference : 1-2 November 2016, Copenhagen, Denmark 2016 / [5] p. : ill https://doi.org/10.1109/NORCHIP.2016.7792916

Databases and Information Systems : proceedings of the 11th International Baltic Conference, Baltic DB&IS 2014 : Tallinn, Estonia, 8-11 June, 2014
2014 http://www.ester.ee/record=b3088507*est

Databases and information systems : proceedings of the Eighth International Baltic Conference, Baltic DBAMPIS 2008 : Tallinn, June 2-5, 2008
2008 http://www.ester.ee/record=b2374996*est

Databases and information systems : proceedings of the Fifth International Baltic Conference : Baltic DB & IS 2002 : Tallinn, June 3-6, 2002
2002 http://www.ester.ee/record=b1641978*est

Databases and information systems VIII : selected papers from the Eleventh International Baltic Conference, DB&IS 2014
2014 https://www.ester.ee/record=b4447206*est

Deadlock-free generic routing algorithms for 3-dimensional Networks-on-Chip with reduced vertical link density topologies
Ying, Haoyuan; Jaiswal, Ashok; **Hollstein, Thomas**; Hofmann, Klaus Journal of systems architecture 2013 / p. 528-542 : ill https://doi.org/10.1016/j.sysarc.2013.03.005 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Decision diagrams - from a mathematical notion to engineering applications
Stankovic, Radomir S.; **Ubar, Raimund-Johannes**; Astola, Jaakko Facta Universitatis [Niš]. Series electronics and energetics 2011 / p. 281-301 : ill http://dx.doi.org/10.2298/FUEE1103281S

Decision diagrams for diagnostic modeling
Ubar, Raimund-Johannes MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 43

Defect-oriented BIST quality analysis
Kruus, Helena; **Ubar, Raimund-Johannes**; **Raik, Jaan** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 153-156 : ill

Defect-oriented test generation and fault simulation in the environment of MOSCITO
Schneider, Andre; Diener, Karl-Heinz; Gramatova, Elena; Fisherova, Maria; **Ivask, Eero**; **Ubar, Raimund-Johannes**; Pleskacz, Witold A.; Kuzmicz, W. BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 303-306 : ill

DefSim - the defective IC
Pleskacz, Witold A.; **Jutman, Artur**; **Ubar, Raimund-Johannes**; **Devadze, Sergei** DATE 2007 : Design Automation and Test in Europe : Nice, France, April 16-20, 2007 2007 / p. s96 (2 p.)

Department of Computer Engineering
Keevallik, Andres; **Ubar, Raimund-Johannes** Research activities / Tallinn Technical University 1993 / p. 75-78 https://www.ester.ee/record=b1053754*est

Dependable embedded systems : FP7 KhAI-ERA project experience
Kharchenko, Vyacheslav; Kulanov, Vitaliy; **Jervan, Gert** 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 26-30 : ill

Design of FPGA-based circuits using hierarchical finite state machines
Skliarova, Iouliia; Sklyarov, Valery; **Sudnitsõn, Aleksander** 2012 http://www.ester.ee/record=b2857138*est

Design space exploration and optimisation for NoC-based timing sensitive systems
Tagel, Mihkel; **Ellervee, Peeter**; **Jervan, Gert** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 177-180 : ill

Design space exploration in multi-level computing systems
Sklyarov, Valery; Skliarova, Iouliia; Silva, João; **Sudnitsõn, Aleksander** CompSysTech'14 : 15th International Conference on Computer Systems and Technologies : Ruse, Bulgaria, June 27-28, 2014 2014 / p. 40-47 : ill https://doi.org/10.1145/2659532.2659616 Conference proceedings at Scopus Article at Scopus

Designing reliable cyber-physical systems : overview associated to the special session at FDL'16
Aleksandrowicz, Gadi; Arbel, Eli; Bloem, Roderick; **Devadze, Sergei**; **Jenihhin, Maksim**; **Jutman, Artur**; **Raik, Jaan**; **Shibin, Konstantin** The 2016 Forum on Specification & Design Languages : proceedings : Bremen, Germany, September 14-16, 2016 2016 / [8] p. : ill https://doi.org/10.1109/FDL.2016.7880382

Developing a data acquisition system for measuring microcontroller energy consumption using LabVIEW
Ruberg, Priit; **Lass, Keijo**; **Ellervee, Peeter** BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 123-126 : ill http://www.ester.ee/record=b2150914*est

DfT-based external test and diagnosis of mesh-like networks on chips = Testitavusel põhinev välise testi ja diagnoosi meetod kahemõõtmelistele kiipvõrkudele
Govind, Vineeth 2009 https://digi.lib.ttu.ee/i/?454 https://www.ester.ee/record=b2539211*est

Diagnostic modeling of digital systems with low- and high-level decision diagrams
Ubar, Raimund-Johannes LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [1] p

Diagnostic software with WEB interface for teaching purposes
Vislogubov, Vladislav; **Jutman, Artur**; **Kruus, Helena**; **Orasson, Elmet**; **Raik, Jaan**; **Ubar, Raimund-Johannes** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 255-258 : ill

Diagnostic test generation for statistical bug localization using evolutionary computation
Gaudesi, Marco; **Jenihhin, Maksim**; **Raik, Jaan**; **Tihhomirov, Valentin**; **Ubar, Raimund-Johannes** Applications of Evolutionary Computation : 17th European Conference, EvoApplications 2014, Granada, Spain, April 23-25, 2014 : revised selected papers 2014 / p. 425-436 : ill https://doi.org/10.1007/978-3-662-45523-4_35 Conference proceeding at Scopus Article at Scopus Conference proceeding at WOS Article at WOS

DIAGNOZER : a laboratory tool for teaching research in diagnosis of electronic systems [Electronic resource]
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Jutman, Artur**; **Raik, Jaan**; Wuttke, Heinz-Dietrich 2009 IEEE International Conference on Microelectronic Systems Education MSE '09 : 25-27 July 2009, San Francisco, California : [proceedings] 2009 / p. 12-15 : ill. [CD-ROM] http://dx.doi.org/10.1109/MSE.2009.5270842

Digitaalsüsteemide diagnostika
Ubar, Raimund-Johannes 2005 http://www.ester.ee/record=b2097071*est

Digital system modeling and synthesis as an introduction to computer systems engineering
Tajammul, Muhammad Adeel; **Azad, Siavoosh Payandeh**; **Ellervee, Peeter** 2015 International Conference on Microelectronic Systems Education : MSE '15 : Pittsburgh, PA, May 20-21, 2015 2015 / p. 52-55 : ill http://dx.doi.org/10.1109/MSE.2015.7160016

Digital test in WEB-based environment
Ivask, Eero 2006 https://www.ester.ee/record=b2158119*est

Discovering logical constructs from Estonian children language = Loogiliste konstruktsioonide avastamine eesti laste keelest
Matsak, Erika 2009 https://www.ester.ee/record=b2557755*est

Diskreetne matemaatika
Lensen, Harri; **Kruus, Margus** 2006 http://www.ester.ee/record=b2223858*est

Diskreetne matemaatika
Lensen, Harri; **Kruus, Margus** 2002 http://www.ester.ee/record=b1850141*est

Distributed approach for parallel exact critical path tracing fault simulation
Ivask, Eero; **Devadze, Sergei**; **Ubar, Raimund-Johannes** International journal of microelectronics and computer science 2010 / p. 165-174 : ill

Double phase fault collapsing with linear complexity in digital circuits
Ubar, Raimund-Johannes; **Jürimägi, Lembit**; **Orasson, Elmet**; **Josifovska, Galina**; **Oyeniran, Adeboye Stephen** DSD 2015 : 18th Euromicro Conference on Digital Systems Design : 26-28 August 2015, Funchal, Madeira, Portugal 2015 / p. 700-705 : ill

DyMeP : an infrastructure to support dynamic memory binding for runtime mapping in CGRAs
Tajammul, Muhammad Adeel; Jafri, Syed Mohammad Asad Hassan; **Ellervee, Peeter**; Hemani, Ahmed; Tenhunen, Hannu; Plosila, Juha 28th International Conference on VLSI Design : held concurrently with 14th International Conference on Embedded Systems : 3-7 January 2015, Bangalore, India : proceedings 2015 / p. 547-552 : ill https://doi.org/10.1109/VLSID.2015.98 Conference proceedings at Scopus Article at Scopus Article at WOS

DyMeP : an infrastructure to support dynamic memory binding for runtime mapping in CGRAs
Tajammul, Muhammad Adeel; Jafri, Syed Mohammad Asad Hassan; **Ellervee, Peeter**; Hemani, Ahmed; Tenhunen, Hannu; Plosila, Juha Doctoral School in Information and Communication Technology : proceedings of doctoral session of BEC 2014 : October 6-8 2014, Laulasmaa 2014 / lk. 19-22 : ill

Dynamic quadrant partitioning adaptive routing algorithm for irregular reduced vertical link density topology 3-dimensional network-on-chips
Ying, Haoyuan; Hofmann, Klaus; **Hollstein, Thomas** Proceedings of the 2014 International Conference on High Performance Computing & Simulation (HPCS 2014) : July 21-25, 2014, Bologna, Italy 2014 / p. 516-522 : ill

EE : Eesti (Estonia)
Ubar, Raimund-Johannes; **Rüstern, Ennu**; **Kruus, Margus** Towards the harmonisation of Electrical and Information Engineering Education in Europe : 2003-2004 2003 / p. 67-74 : ill http://www.ester.ee/record=b2300874*est

Eestilt Euroopale : [Euroopa nanotehnika foorumil osales Eestist Raamprogrammi FP7 projekt DIAMOND, mida juhib TTÜ arvutitehnika instituudi professor Jaan Raik]
Ubar, Raimund-Johannes Mente et Manu 2012 / lk. 8 : fot https://www.ester.ee/record=b1242496*est

Effective scalable IEEE 1687 instrumentation network for fault management
Jutman, Artur; **Shibin, Konstantin**; **Devadze, Sergei** IEEE design & test 2013 / p. 26-35 : ill https://doi.org/10.1109/MDAT.2013.2278535 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

E-learning tools for teaching self-test of digital electronics
Jutman, Artur; Gramatova, Elena; Pikula, T.; **Ubar, Raimund-Johannes** 15 EAEEIE International Conference on Innovation in Education for Electrical and Information Engineering : Sofia, Bulgaria, May 27-29, 2004 2004 / p. 267-272 : ill

Elektroonika kui Eesti innovatsioonisüsteemi infrastruktuur
Min, Mart; **Rang, Toomas**; **Ubar, Raimund-Johannes** Eesti teadlaste kongress, 11.-15. augustini 1996. a. Tallinnas : ettekannete kokkuvõtted 1996 / lk. 265 https://www.ester.ee/record=b1052731*est

Elmet Orasson tabab laskesporti
Orasson, Elmet Mente et Manu 2014 / lk. 18-19 : fot https://www.ester.ee/record=b1242496*est

Embedded software solutions for development of marine navigation light system = Sardtarkvara lahendused valgusnavigatsiooni süsteemide arendusel
Moorits, Erkki 2016 http://digi.lib.ttu.ee/i/?6383

Environment for fault simulation acceleration on FPGA
Ellervee, Peeter; **Raik, Jaan**; Tihhomirov, Valentin BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 217-220 : ill

Environment for the analysis of functional self-test quality in digital systems
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Kruus, Helena**; **Aarna, Margit**; **Devadze, Sergei** Proceedings of the Estonian Academy of Sciences 2014 / p. 151-162 : ill https://artiklid.elnet.ee/record=b2673964*est https://doi.org/10.3176/proc.2014.2.05 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Estonia : e-Design and EDA
Jenihhin, Maksim 50th DAC Global Forum 2013 / [2] p

Estonian eGovernment services : lesson learned
Kalja, Ahto; **Põld, Janari**; **Robal, Tarmo**; Vallner, Uuno; **Viies, Vladimir** Proceedings of PICMET'13 : Technology Management in the IT-Driven Services : [July 28-August 1, 2013, San Jose, California, USA] 2013 / p. 562-568 : ill

Evaluation of basic project management activities : study in software industry
Lepmets, Marion 2007 https://www.ester.ee/record=b2302044*est

Evaluation of SysML software for teaching systems engineering basics
Kruus, Helena; **Jervan, Gert** Proceedings of the 25th International Conference on European Association for Education in Electrical and Information Engineering : 30 May-June 2014, Cesme, Türkiye 2014 / p. 29-32 : ill

Evolutionary approach to the functional test generation for digital circuits
Skobtsov, Y.A.; Ivanov, D.E.; Skobtsov, V.Y.; **Ubar, Raimund-Johannes** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 229-232 : ill

Exact static compaction of independent test sequences
Raik, Jaan; **Jutman, Artur**; **Ubar, Raimund-Johannes** BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 315-318 : ill

Expectations of software development practitioners for non-technical clients
Ojastu, Deniss; **Robal, Tarmo**; **Kalja, Ahto** Databases and information systems VIII : selected papers from the Eleventh International Baltic Conference, DB&IS 2014 2014 / p. 317-330 : ill https://doi.org/10.3233/978-1-61499-458-9-317 Conference proceedings at Scopus Article at Scopus Article at WOS

Extended checkers for control part of routers in network-on-chips

Hariharan, Ranganathan; **Niazmand, Behrad**; **Hollstein, Thomas**; **Raik, Jaan**; **Jervan, Gert** MEDIAN 2015 : the 4th Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : March 13, 2015, Grenoble, France 2015 / p. 36-39 : ill

Extended checkers for logic-based distributed routing in network-on-chips
Niazmand, Behrad; **Hariharan, Ranganathan**; **Govind, Vineeth**; **Jervan, Gert**; **Hollstein, Thomas**; **Raik, Jaan** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 83-86 : ill

Extended checkers for logic-based distributed routing in network-on-chips
Niazmand, Behrad; **Hariharan, Ranganathan**; **Govind, Vineeth**; **Jervan, Gert**; **Hollstein, Thomas**; **Raik, Jaan** BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 77-80 : ill

Extensible open-source framework for translating RTL VHDL IP cores to SystemC
Saif Abrar, Syed; **Jenihhin, Maksim**; **Raik, Jaan** Proceedings of the 2013 IEEE 16th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 8-10, 2013, Karlovy Vary, Czech Republic 2013 / p. 112-115

Fast and optimized task allocation method for low vertical link density 3-Dimensional Networks-on-Chip based many core systems
Ying, Haoyuan; **Hollstein, Thomas**; Hofmann, Klaus Proceedings : Design, Automation & Test in Europe : Grenoble, France, March 18-22, 2013 2013 / p. 1777-1782 : ill

Fast data sort based on searching networks with ring pipeline
Sklyarov, Valery; Skliarova, Iouliia; **Sudnitsõn, Aleksander** Elektronika ir elektrotechnika = Electronics and electrical engineering 2016 / p. 58-62 : ill https://doi.org/10.5755/j01.eie.22.4.15920 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Fast extended test access via JTAG and FPGAs
Devadze, Sergei; **Jutman, Artur**; **Aleksejev, Igor**; **Ubar, Raimund-Johannes** International Test Conference 2009 : November 1 - November 6, 2009, Austin Convention Center, Austin, Texas USA : proceedings 2009 / p. 1-7 : ill
http://dx.doi.org/10.1109/TEST.2009.5355668

Fast matrix covering in all programmable systems-on-chip
Sklyarov, Valery; Skliarova, Iouliia; **Rjabov, Artjom**; **Sudnitsõn, Aleksander** Elektronika ir elektrotechnika = Electronics and electrical engineering 2014 / p. 150-153 : ill https://doi.org/10.5755/j01.eee.20.5.7116 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Fast static compaction of tests composed of independent sequences : basic properties and comparison of methods
Raik, Jaan; **Jutman, Artur**; **Ubar, Raimund-Johannes** The 9th IEEE International Conference on Electronics, Circuits and Systems : ICECS 2002 : September 15-18, 2002, Dubrovnik, Croatia. Volume II 2002 / p. 445-448 : ill
http://dx.doi.org/10.1109/ICECS.2002.1046190 https://ieeexplore.ieee.org/document/1046190

Fault collapsing in digital circuits using fast fault dominance and equivalence analysis with SSBDDs
Ubar, Raimund-Johannes; **Jürimägi, Lembit**; **Orasson, Elmet**; **Raik, Jaan** VLSI-SoC : Design for Reliability, Security, and Low Power : 23rd IFIP WG 10.5/IEEE International Conference on Very Large Scale Integration, VLSI-SoC 2015 Daejeon, Korea, October 5-7, 2015 : revised selected papers 2016 / p. 23-45 : ill https://doi.org/10.1007/978-3-319-46097-0_2 Conference Proceedings at Scopus Article at Scopus Article at WOS

Fault diagnosis in integrated circuits with BIST
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Raik, Jaan**; **Evartson, Teet**; **Lensen, Harri** 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 604-610 : ill http://dx.doi.org/10.1109/DSD.2007.4341530

Fault effect reasoning in digital systems by topological view on low- and high-level decision diagrams
Ubar, Raimund-Johannes Вестник Томского государственного университета. Управление, вычислительная техника и информатика 2014 / p. 99-113 : ill http://journals.tsu.ru/informatics/&journal_page=archive&id=923&article_id=12107

Fault management instrumentation network based on IEEE P1687 IJTAG
Shibin, Konstantin; **Jutman, Artur**; **Devadze, Sergei** European Test Symposium (ETS), 2013, Avignon, France 2013

Fault oriented test pattern generation for sequential circuits using Genetic Algorithms
Ivask, Eero; **Raik, Jaan**; **Ubar, Raimund-Johannes** The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 129-132 : ill

Fault simulation and code coverage analysis of RTL designs using high-level decision diagrams = Rikete simuleerimine ja koodikatte analüüs register-siirde tasemel kasutades kõrgtaseme otsustusdiagramme

Reinsalu, Uljana 2013 https://www.ester.ee/record=b2963595*est

Fault simulation of digital systems = Digitaalsüsteemide rikete simuleerimine
Devadze, Sergei 2009 https://digi.lib.ttu.ee/i/?445 https://www.ester.ee/record=b2508727*est

Fault simulation with parallel critical path tracing for combinational circuits using structurally synthesized BDDs
Devadze, Sergei; **Raik, Jaan**; **Jutman, Artur**; **Ubar, Raimund-Johannes** 7th IEEE Latin American Test Workshop LATW'06 : Buenos Aires, Argentina, March 26th-29th, 2006 : proceedings 2006 / p. 97-102 : ill

Fault simulation with parallel exact critical path tracing in multiple core environment
Gorev, Maksim; **Ubar, Raimund-Johannes**; **Devadze, Sergei** 2015 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2015 / p. 1180-1185 : ill

Fault-tolerant scheduling of mixed-critical applications on multi-processor platforms
Bagheri, Mehrdad; **Jervan, Gert** 2014 International Conference on Embedded and Ubiquitous Computing : EUC 2014 : 26-28 August 2014, Milano, Italy : proceedings 2014 / p. 25-32 : ill

Finite state machine synthesis for low power using input-disabling precomputation architectures
Sudnitsõn, Aleksander The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 137-140 : ill

Flexible controller for educational robot kit
Ruberg, Priit; **Guitar, Aivar**; **Ellervee, Peeter** 2015 International Conference on Microelectronic Systems Education : MSE '15 : Pittsburgh, PA, May 20-21, 2015 2015 / p. 17-20 : ill http://dx.doi.org/10.1109/MSE.2015.7160007

Foreword
Rang, Toomas; **Min, Mart**; **Ubar, Raimund-Johannes** BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 3 https://www.ester.ee/record=b2150914*est

Foreword to the 12th IEEE DDECS Symposium
Pliva, Zdenek; Manhaeve, Hans; Renovell, Michel; Novak, Ondrej; **Ubar, Raimund-Johannes**; Drabkova, Jindra Proceedings of the 2009 IEEE Symposium on Design and Diagnostics of Electronic Circuits and Systems : April 15-17, 2009, Liberec, Czech Republic 2009 / p. iii http://dx.doi.org/10.1109/DDECS.2009.5012081

Formal verification and error correction on high-level decision diagrams = Formaalne verifitseerimine ja vigade parandamine kõrgtasemelistel otsustusdiagrammidel
Karputkin, Anton 2012

FP7 DIAMOND : design error diagnosis and correction success stories
Raik, Jaan; **Jenihhin, Maksim**; Könighofer, Robert European Test Symposium (ETS), 2013, Avignon, France 2013 / p. 1-6

FPGA-based accelerators for parallel data sort
Sklyarov, Valery; Skliarova, Iouliia; **Sudnitsõn, Aleksander** Applied computer systems 2014 / p. 53-63 : ill

FPGA-based embedded virtual instrumentation = FPGA-sisesed virtuaalsed test- ja mõõtevahendid
Aleksejev, Igor 2013 http://www.ester.ee/record=b2927687*est

FPGA-based time and cost effective Hamming weight comparators for binary vectors
Sklyarov, Valery; Skliarova, Iouliia; **Sudnitsõn, Aleksander**; **Kruus, Margus** Proceedings : EUROCON 2015 : Salamanca, Spain, 8th-11th September 2015 / p. 328-333 : ill http://dx.doi.org/10.1109/EUROCON.2015.7313700

A framework for area-efficient concurrent online checkers design
Saltarelli, Pietro; **Niazmand, Behrad**; **Hariharan, Ranganathan**; **Raik, Jaan**; **Jervan, Gert**; **Hollstein, Thomas** MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 64-69 : ill

A framework for combining concurrent checking and online embedded test for low-latency fault detection in NoC routers
Saltarelli, Pietro; **Niazmand, Behrad**; **Raik, Jaan**; **Govind, Vineeth**; **Hollstein, Thomas**; **Jervan, Gert**; **Hariharan, Ranganathan** NOCS '15 : International Symposium on Networks-on-Chip : Vancouver, BC, Canada, September 28-30, 2015 2015 / [8] p. : ill http://dx.doi.org/10.1145/2786572.2788713

A framework for comprehensive automated evaluation of concurrent online checkers
Saltarelli, Pietro; **Niazmand, Behrad**; **Raik, Jaan**; **Hariharan, Ranganathan**; **Jervan, Gert**; **Hollstein, Thomas** Euromicro Conference on Digital System Design : DSD 2015 : 26-28 August 2015, Funchal, Madeira, Portugal : proceedings 2015 / p. 288-292 : ill http://dx.doi.org/10.1109/DSD.2015.15

A framework for improving web application user interfaces through immediate evaluation
Marenkov, Jevgeni; **Robal, Tarmo**; **Kalja, Ahto** Databases and information systems IX : selected papers from the twelfth International Baltic Conference, DB&IS 2016 2016 / p. 283-296 : ill https://doi.org/10.3233/978-1-61499-714-6-283 Article collection metrics at Scopus Article at Scopus Article at WOS

A framework of awareness for artificial subjects
Jantsch, Axel; **Tammemäe, Kalle** CODES '14 : proceedings of the 2014 International Conference on Hardware/Software Codesign and System Synthesis 2014 / [3] p

FSM decomposition using shift registers
Kruus, Margus; **Lensen, Harri** The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 141-144 : ill

FSMD RTL design manipulation for clock interface abstraction
Abrar, Syed Saif; **Jenihhin, Maksim**; **Raik, Jaan** 2015 International Conference on Advances in Computing, Communications and Informatics (ICACCI) : 10-13 August 2015, Kerala, India 2015 / p. 463-468 : ill http://dx.doi.org/10.1109/ICACCI.2015.7275652

Functional self-test of high-performance pipe-lined signal processing architectures
Gorev, Maksim; **Ubar, Raimund-Johannes**; **Ellervee, Peeter**; **Devadze, Sergei**; **Raik, Jaan**; **Min, Mart** Microprocessors and microsystems 2015 / p. 909-918 : ill https://doi.org/10.1016/j.micpro.2014.11.002 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Functional test generation for finite state machines
Ubar, Raimund-Johannes; **Brik, Marina**; **Jutman, Artur**; **Raik, Jaan**; Bengtsson, Tomas; Kumar, Shashi BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 205-208 : ill

GA-based test generation for sequential circuits
Brik, Marina; **Raik, Jaan**; **Ubar, Raimund-Johannes**; **Ivask, Eero** Proceedings of East–West Design & Test Workshop (EWDTW'04) : Yalta, Alushta, Crimea, Ukraine, September 23-26, 2004 2004 / p. 30-34

Gate-level modelling of NBTI-induced delays under process variations
Copetti, Thiago; Cardoso Medeiros, Guilherme; Bolzani Poehls, Leticia; Vargas, Fabian; **Kostin, Sergei**; **Jenihhin, Maksim**; **Raik, Jaan**; **Ubar, Raimund-Johannes** LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguacu, Brazil, 6th-9th April 2016 2016 / p. 75-80 : ill http://dx.doi.org/10.1109/LATW.2016.7483343

A generic synthesizable NoC switch with a scalable testbench
Govind, Vineeth; **Raik, Jaan**; **Ubar, Raimund-Johannes** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 91-94 : ill

Graph embedding in boolean hypercube
Fomina, Jelena; Zakrevskij, Arkadij BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 131-134 : ill

Greedy alternative for the static compaction of sequential circuit test sequences
Raik, Jaan The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 133-136 : ill

Grey box identification of fractional-order system models from frequency domain data
Tepljakov, Aleksei; **Petlenkov, Eduard**; **Belikov, Juri** 41th International Conference on Telecommunications and Signal Processing : July 4-6, 2018, Athens, Greece : proceedings 2018 / p. 319-322 : ill https://doi.org/10.1109/TSP.2018.8441247

GSNoC — the comprehensive design platform for 3-dimensional Networks-on-Chip based many core embedded systems
Ying, Haoyuan; **Hollstein, Thomas**; Hofmann, Klaus Proceedings of the 2013 International Conference on High Performance Computing & Simulation (HPCS 2013) : July 1-July 5, 2013, Helsinki, Finland 2013 / p. 217-223 : ill

Guest editorial
Ellervee, Peeter; Nurmi, Jari Microprocessors and microsystems 2013 / p. 430-431

Hardware accelerators for information retrieval and data mining
Sklyarov, Valery; Skliarova, Iouliia; Silva, João; **Sudnitsõn, Aleksander**; **Rjabov, Artjom** 2015 International Conference on Information and Communication Technology Research (ICTRC2015) : Abu Dhabi, United Arab Emirates, May 17-19, 2015 2015 / p. 202-205 : ill http://dx.doi.org/10.1109/ICTRC.2015.7156457

Hardware close programming for freshmen
Kruus, Helena; **Brik, Marina**; **Kruus, Margus**; **Ruberg, Priit**; **Viies, Vladimir**; **Ellervee, Peeter** 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 93-96 : ill

Hardware implementation of face recognition using low precision representation
Dwivedi, Sai Kumar; **Azad, Siavoosh Payandeh**; **Ellervee, Peeter**; Dash, Ratnakar BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 63-66 : ill http://www.ester.ee/record=b2150914*est

Hardware implementation of recursive sorting algorithms using tree-like structures and HFSM models = Rekursiivsete sortimisalgoritmide riistvaraline realiseerimine kasutades puulaadseid struktuure ja HFSM mudeleid
Mihhailov, Dmitri 2011 https://www.ester.ee/record=b2748823*est

Hardware modeling for design verification and debug = Riistvara modelleerimine disaini verifitseerimise ja silumise jaoks
Tšepurov, Anton 2013 https://www.ester.ee/record=b2963501*est

Hardware/software co-design for programmable systems-on-chip
Sklyarov, Valery; Skliarova, Iouliia; Silva, João; Rjabov, Artjom; **Sudnitsõn, Aleksander**; Cardoso, Cláudia 2014 http://www.ester.ee/record=b3087107*est

Hardware/software co-design in extensible processing platforms for combinatorial search algorithms
Skliarova, Iouliia; Sklyarov, Valery; **Rjabov, Artjom**; **Sudnitsõn, Aleksander** MELECON 2014 : 2014 17th IEEE Mediterranean Electrotechnical Conference : 13-16 April 2014, Beirut, Lebanon 2014 / p. 462-466 : ill https://doi.org/10.1109/MELCON.2014.6820578 Conference proceedings at Scopus Article at Scopus Article at WOS

A hardware/software co-design reconfigurable network-on-chip FPGA emulation method
Ying, Haoyuan; **Hollstein, Thomas**; Hofmann, Klaus 2014 9th International Symposium on Reconfigurable and Communication-Centric Systems-on-Chip (ReCoSoC) : Montpellier, France, 26-28 May, 2014 2014 / [8] p. : ill

Hardware-based systems for partial sorting of streaming data
Rjabov, Artjom BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 59-62 : ill http://www.ester.ee/record=b2150914*est

Hierarchical fault diagnosis in embedded digital systems with multi-level decision diagrams [Electronic resource]
Ubar, Raimund-Johannes; **Evartson, Teet**; **Lensen, Harri**; **Aarna, Margit** 5th International Conference on Industrial Automation = Cinquieme Conference Internationale sur l'Automatisation Industrielle : June 11-13, 2007, Montreal, Canada 2007 / [6] p. [CD-ROM]

Hierarchical fault simulation for finite state machines
Brik, Marina; **Raik, Jaan**; **Ubar, Raimund-Johannes** The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 145-148 : ill

Hierarchical identification of NBTI-critical gates in nanoscale logic
Kostin, Sergei; **Raik, Jaan**; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim** LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

Hierarchical identification of untestable faults in sequential circuits
Raik, Jaan; **Ubar, Raimund-Johannes**; **Krivenko, Anna**; **Kruus, Margus** 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 668-671 : ill http://dx.doi.org/10.1109/DSD.2007.4341539

Hierarchical test generation for digital circuits represented by Decision Diagrams : thesis on informatics and system engineering
Raik, Jaan 2001 https://www.ester.ee/record=b1578107*est

Hierarchical test pattern generation and untestability identification techniques for synchronous sequential circuits = Hierarhilised testintegreerimise ja mittetestitavuse identifitseerimise meetodid sünkroonsetele järjestikskeemidele
Rannaste, Anna 2010 https://www.ester.ee/record=b2637391*est

High-level decision diagram based fault models for targeting FSMs
Raik, Jaan; **Ubar, Raimund-Johannes**; **Viilukas, Taavi** 9th EUROMICRO Conference on Digital Systems Design : Architectures, Methods and Tools (DSD 2006) : 30 August 2006-1 September 2006, Cavtat near Dubrovnik, Croatia : proceedings 2006 / p. 353-358 : ill http://dx.doi.org/10.1109/DSD.2006.60

High-level decision diagrams based coverage metrics for verification and test
Jenihhin, Maksim; **Raik, Jaan**; **Tšepurov, Anton**; **Reinsalu, Uljana**; **Ubar, Raimund-Johannes** LATW 2009 : 10th IEEE Latin

American Test Workshop : Buzios, Rio de Janero, Brazil, March 2-5, 2009 2009 / [6] p. : ill http://dx.doi.org/10.1109/LATW.2009.4813792

High-level design error diagnosis using backtrace on decision diagrams
Raik, Jaan; **Repinski, Urmas**; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim**; **Tšepurov, Anton** 28th Norchip Conference : Tampere, Finland, 15-16 November 2010 : conference program and papers 2010 / [4] p. : ill http://dx.doi.org/10.1109/NORCHIP.2010.5669486

High-level modeling and testing of multiple control faults in digital systems
Jasnetski, Artjom; **Oyeniran, Adeboye Stephen**; **Tšertov, Anton**; Schölzel, Mario; **Ubar, Raimund-Johannes** Formal proceedings of the 2016 IEEE 19th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 20-22, 2016, Košice, Slovakia 2016 / [6] p. : ill http://dx.doi.org/10.1109/DDECS.2016.7482445

High-level synthesis and test in the MOSCITO-based virtual laboratory
Schneider, Andre; Diener, Karl-Heinz; **Jervan, Gert**; Peng, Z.; **Raik, Jaan**; **Ubar, Raimund-Johannes**; Hollstein, Thomas; Glesner, M. BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 287-290 : ill

High-level synthesis of control and memory intensive applications : thesis submitted to the Royal Institute of Technology in partial fulfillment of the requirements for the degree of Doctor of Technology
Ellervee, Peeter 2000

High-performance information processing in distributed computing systems
Sklyarov, Valery; **Rjabov, Artjom**; Skliarova, Iouliia; **Sudnitsõn, Aleksander** International journal of innovative computing, information and control 2016 / p. 139-160 : ill https://www.researchgate.net/publication/297047447_High-performance_information_processing_in_distributed_computing_systems Journal metrics at Scopus Article at Scopus

Holistic approach for Fault-Tolerant Network-on-Chip based many-core systems [Online resource]
Azad, Siavoosh Payandeh; **Niazmand, Behrad**; **Raik, Jaan**; **Jervan, Gert**; **Hollstein, Thomas** arXiv.org 2016 / [8] p. : ill

How to generate high quality tests for digital systems
Ubar, Raimund-Johannes; **Aarna, Margit**; **Kruus, Helena**; **Raik, Jaan** 2004 International Semiconductor Conference : 27th edition, October 4-6, 2004, Sinaia, Romania : CAS 2004 proceedings. Volume 2 2004 / p. 459-462 : ill http://dx.doi.org/10.1109/SMICND.2004.1403048

Hybrid BIST optimization using reseeding and test set compaction
Jervan, Gert; **Orasson, Elmet**; **Kruus, Helena**; **Ubar, Raimund-Johannes** 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 596-603 : ill http://dx.doi.org/10.1109/DSD.2007.4341529

Hybrid BIST scheduling for NoC-based SoCs
Jervan, Gert; **Shchenova, Tatjana**; **Ubar, Raimund-Johannes** Proceedings [of] 24th IEEE Norchip Conference : Linköping, Sweden, 20-21 November 2006 2006 / p. 141-144 : ill https://ieeexplore.ieee.org/document/4126966

Hybrid built-in self-test : methods and tools for analysis and optimization of BIST = Sisseehitatud hübriidne isetestimine : meetodid ja vahendid analüüsiks ning optimeerimiseks
Orasson, Elmet 2007 https://www.ester.ee/record=b2305436*est

Hybrid functional BIST for digital systems
Mazurova, Natalja; **Smahtina, Julia**; **Ubar, Raimund-Johannes** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 205-208 : ill

Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits
Jenihhin, Maksim; Squillero, Giovanni; **Tihhomirov, Valentin**; **Kostin, Sergei**; **Raik, Jaan**; **Ubar, Raimund-Johannes** Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill https://doi.org/10.1007/s10836-016-5589-x Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Identification and rejuvenation of NBTI-critical paths in nanoscale logic circuits
Jenihhin, Maksim 1st International Workshop on Reliability and Aging in Forthcoming Electronic Systems : May 28-29, 2015, Cluj-Napoca, Romania 2015 / [1] p

Identifying NBTI-critical paths in nanoscale logic
Ubar, Raimund-Johannes; Vargas, Fabian; **Jenihhin, Maksim**; **Raik, Jaan**; **Kostin, Sergei**; Bolzani Poehls, Leticia 16th Euromicro Conference series on Digital System Design : DSD 2013 : proceedings : 4-6 September 2013, Santander, Spain 2013 / p. 136-141 : ill

IEEE Eesti sektsioon on 10-aastane

Tammemäe, Kalle; **Kukk, Vello** Elektriala 2016 / lk. 14-15 http://www.ester.ee/record=b1240496*est https://artiklid.elnet.ee/record=b2803323*est

IEEE Student Branch Tallinn University of Technolgy
Tammemäe, Kalle Studioosus 2014 / lk. 12 https://www.ester.ee/record=b1558644*est

Implementation of parallel operations over streams in extensible processing platforms
Sklyarov, Valery; Skliarova, Iouliia; **Rjabov, Artjom**; **Sudnitsõn, Aleksander** 2013 IEEE 56th International Midwest Symposium on Circuits and Systems (MWSCAS) : August 4-7, 2013, Columbus, Ohio : [proceedings] 2013 / p. 852-855 : ill https://doi.org/10.1109/MWSCAS.2013.6674783 Conference Proceedings at Scopus Article at Scopus

Implementing quality assessment model in IT project
Marenkov, Mihhail; Valdlo, Taavi; **Viies, Vladimir** EURAS proceedings 2014 : cooperation between standardisation organisations and the scientific and academic community 2014 / p. 107-120

Improved VHDL input for high-level synthesis tool xTractor
Ellervee, Peeter; **Ivask, Eero**; **Kruus, Margus** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 87-90 : ill

Improving sophisticated self-service portal user interfaces : a study on user click behaviour
Marenkov, Jevgeni; **Robal, Tarmo**; **Kalja, Ahto** Databases and Information Systems : proceedings of the 11th International Baltic Conference, Baltic DB&IS 2014 : Tallinn, Estonia, 8-11 June, 2014 2014 / p. 159-170 : ill

Increasing the speed of delay simulation in digital circuits
Ubar, Raimund-Johannes; **Jutman, Artur** The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 31-34 : ill

Informaatika teoreetilised alused : struktuurne aspekt
Lorents, Peeter 2001 https://www.ester.ee/record=b1056267*est

Infotehnika teaduskond : lühiteave
1998 http://www.ester.ee/record=b1061288*est

In-system programming of non-volatile memories on microprocessor-centric boards
Tšertov, Anton; **Devadze, Sergei**; **Jutman, Artur**; **Jasnetski, Artjom** International journal of microelectronics and computer science 2014 / p. 25-34 : ill

Integrated design and test generation under Internet based environment MOSCITO
Schneider, Andre; **Ivask, Eero**; **Ubar, Raimund-Johannes** Euromicro Symposium on Digital System Design : Architectures, Methods and Tools : September 4-6, 2002, Dortmund, Germany : proceedings 2002 / p. 187-194 : ill http://dx.doi.org/10.1109/DSD.2002.1115368

Integrated modelling, fault management, verification and reliable design environment for cyber-physical systems
Raik, Jaan; Rauwerda, Gerard; Zhao, Yong; **Shibin, Konstantin** MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 74

Integration of high-level synthesis to the courses on reconfigurable digital systems
Sklyarov, Valery; Skliarova, Iouliia; **Sudnitsõn, Aleksander**; **Kruus, Margus** 2015 38th International Convention on Information and Communication Technology, Electronics and Microelectronics (MIPRO) : May 25-29, 2015, Opatija, Croatia : proceedings 2015 / p. 166-171 : ill http://dx.doi.org/10.1109/MIPRO.2015.7160258

Interactions of Zynq-7000 devices with general purpose computers through PCI-express : a case study [Electronic resource]
Rjabov, Artjom; **Sudnitsõn, Aleksander**; Sklyarov, Valery; Skliarova, Iouliia Proceedings of the 18th Mediterranean Electrotechnical Conference MELECON 2016 : 18-20 April 2016, Limassol, Cyprus 2016 / [4] p. : ill. [CD-ROM] https://doi.org/10.1109/MELCON.2016.7495400

Internet-based testability-driven test generation in the virtual environment MOSCITO
Schneider, Andre; Diener, Karl-Heinz; Elst, G.; **Ivask, Eero**; **Raik, Jaan**; **Ubar, Raimund-Johannes** International Federation for Information Processing IFIP : International Workshop on IP-Based SoC Design 2002 : proceedings : Grenoble, October 30-31, 2002 2002 / p. 357-362 : ill http://publica.fraunhofer.de/dokumente/N-287433.html

Investigation and development of test generation methods for control part of digital systems
Brik, Marina 2002 http://www.ester.ee/record=b1688656*est

Involving students in teaching process — encouraging student-generated content in ICT studies

Kruus, Helena; **Ellervee, Peeter**; **Robal, Tarmo**; **Ruberg, Priit**; **Kruus, Margus** Proceedings of the 24th International Conference on European Association for Education in Electrical and Information Engineering : 30-31 May 2013, Chania, Greece 2013 / p. 76-81 : ill

Jaak Aaviksoo tuleb rektoriks kinnitada
Jervan, Gert Eesti Päevaleht 2015 / lk. 11 https://epl.delfi.ee/artikkel/71821559/jaak-aaviksoo-tuleb-rektoriks-kinnitada

Java technology based training system for teaching digital design and test
Devadze, Sergei; **Jutman, Artur**; **Sudnitsõn, Aleksander**; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 283-286 : ill

Kahekiiruselise mitmemõõtmelise diskreetse objekti uurimine : [magistritöö] : õppesuund: arvuti- ja süsteemitehnika
Astrov, Igor 1992 http://www.ester.ee/record=b2676838*est

Kakskümmend aastat hiljem : [vestlus arvutisüsteemide dignostika ja verifitseerimise õppetooli professori Jaan Raikiga]
Raik, Jaan Mente et Manu 2013 / lk. 10-12 : fot https://www.ester.ee/record=b1242496*est

20 aastat maailma testiteaduse tippkonkurentsis
Ubar, Raimund-Johannes Mente et Manu 2015 / lk. 12-13 : fot https://artiklid.elnet.ee/record=b2749536*est

Kas oleme õigel teel?
Ubar, Raimund-Johannes Sirp 2016 / lk. 10-11 https://www.sirp.ee/s1-artiklid/c21-teadus/kas-oleme-oigel-teel/

Keel ja loogika
Lorents, Peeter 2000 https://www.ester.ee/record=b1372695*est

Kuidas fookustada korraga kaugele ja lähedale, ehk, Kuidas ülikool saaks paremini teenida ühiskonda
Ubar, Raimund-Johannes Tallinna Tehnikaülikooli aastaraamat 2009 2010 / lk. 13-15 https://www.ester.ee/record=b1212786*est

Kuidas teemant tehnikaülikooli tuli
Raik, Jaan Tallinna Tehnikaülikooli aastaraamat 2009 2010 / lk. 40-43 : ill https://www.ester.ee/record=b1212786*est

Laboratory framework TEAM for investigating the dependability issues of microprocessor systems
Jasnetski, Artjom; **Tšertov, Anton**; **Ubar, Raimund-Johannes**; **Kruus, Helena** 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 80-83 : ill

Layout to logic defect analysis for hierarchical test generation
Jenihhin, Maksim; **Raik, Jaan**; **Ubar, Raimund-Johannes**; Pleskacz, Witold A.; Rakowski, Michal Proceedings of the 2007 IEEE Workshop on Design and Diagnostic Circuits and Systems : April 11-13, 2007, Krakow, Poland 2007 / p. 35-40 : ill http://dx.doi.org/10.1109/DDECS.2007.4295251

LFSR polynomial and seed selection using genetic algorithm
Aleksejev, E.; **Jutman, Artur**; **Ubar, Raimund-Johannes** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 179-182 : ill

Logic simulation and fault collapsing with shared structurally synthesized BDDs
Mironov, Dmitri; **Ubar, Raimund-Johannes**; **Raik, Jaan** 2014 19th IEEE European Test Symposium (ETS) : May 26th-30th, 2014, Paderborn, Germany : proceedings 2014 / [2] p. : ill

Logic-based implementation of fault-tolerant routing in 3D Network-on-Chips
Niazmand, Behrad; **Azad, Siavoosh Payandeh**; Flich, Jose; **Raik, Jaan**; **Jervan, Gert**; **Hollstein, Thomas** 2016 Tenth IEEE/ACM International Symposium on Networks-on-Chip (NOCS) : Nara, Japan, 31 August - 2 September 2016 2016 / [8] p. : ill https://doi.org/10.1109/NOCS.2016.7579317

Loodetavasti ajame ühist asja
Kruus, Margus Mente et Manu 2016 / lk. 4-5 : fot https://artiklid.elnet.ee/record=b2756897*est

Low power finite state machine synthesis
Fomina, Jelena 2005 https://www.ester.ee/record=b2097121*est

Lower bounds of the size of shared structurally synthesized BDDs
Ubar, Raimund-Johannes; **Mironov, Dmitri** Proceedings of the 2014 IEEE 17th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 23-25, 2014, Warsaw, Poland 2014 / p. 77-82 : ill

Läti keelel on teadustöös suurem roll kui eesti keelel
Haav, Hele-Mai; **Kalja, Ahto**; **Nõges, Krõõt** Mente et Manu 2014 / lk. 16-17 : fot https://artiklid.elnet.ee/record=b2674038*est

Macro level defect-oriented diagnosability of digital circuits
Kostin, Sergei; **Ubar, Raimund-Johannes**; **Raik, Jaan** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 149-152 : ill

Managing knowledge in Web portals for improved customer loyalty and satisfaction
Robal, Tarmo; **Kalja, Ahto** Proceedings of PICMET'13 : Technology Management in the IT-Driven Services : [July 28-August 1, 2013, San Jose, California, USA] 2013 / p. 1207-1216 : ill

Managing software engineering competences with domain ontology for customer and team profiling and training
Robal, Tarmo; **Ojastu, Deniss**; **Kalja, Ahto**; Jaakkola, Hannu PICMET '15 : proceedings : Management of the Technology Age 2015 / p. 1369-1376 : ill http://dx.doi.org/10.1109/PICMET.2015.7273171

Managing software engineering competences with domain ontology for customer and team profiling and training
Robal, Tarmo; **Ojastu, Deniss**; **Kalja, Ahto**; Jaakkola, Hannu PICMET '15 Conference : Management of the Technology Age : August 2-6, 2015, Portland, Oregon, USA : conference bulletin 2015 / p. 62

Mapping of VHDL structures for generic EDA database format IRSYD
Ivask, Eero; **Ellervee, Peeter** The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 317-320 : ill

Measuring and identifying aging-critical paths in FPGAs
Pfeifer, Petr; **Raik, Jaan**; **Jenihhin, Maksim**; **Ubar, Raimund-Johannes**; Pliva, Zdenek MEDIAN 2015 : the 4th Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : March 13, 2015, Grenoble, France 2015 / p. 56-61 : ill

A method for crosstalk fault detection in on-chip buses
Bengtsson, Tomas; **Jutman, Artur**; **Ubar, Raimund-Johannes**; Kumar, Shashi Norchip : proceedings : Oulu, Finland, 21-22 November 2005 2005 / p. 285-288 : ill https://doi.org/10.1109/NORCHP.2005.1597045

Methode et outil de prototypage des systemes integres sur FPGAs : [doktoriväitekiri]
Krupnova, Helena 1999

Microcontroller energy consumption estimation based on software analysis for embedded systems
Ruberg, Priit; **Lass, Keijo**; **Ellervee, Peeter** 2015 Nordic Circuits and Systems Conference (NORCAS) : NORCHIP & International Symposium on System-on-Chip (SoC) : 1st IEEE NORCAS Conference : 26-28 October 2015, Oslo, Norway 2015 / [4] p. : ill http://dx.doi.org/10.1109/NORCHIP.2015.7364397

Microprocessor-based system test using debug interface
Devadze, Sergei; **Jutman, Artur**; **Tšertov, Anton**; Instenberg, Martin; **Ubar, Raimund-Johannes** 26th Norchip Conference : Tallinn, Estonia, 17-18 November 2008 : formal proceedings 2008 / p. 98-101 : ill http://dx.doi.org/10.1109/NORCHP.2008.4738291

Mida peaks teaduspoliitikas reformima? : kui hindamisel jääb puudu kompetentsusest, on bibliomeetria see faktor, mis alati kõneleb täiel häälel ja vastuvaidlematult
Ubar, Raimund-Johannes Sirp 2014 / lk. 34-35 https://www.sirp.ee/s1-artiklid/c9-sotsiaalia/mida-peaks-teaduspoliitikas-reformima/

Mida vinget tõi lõppev aasta tehnikailma? : [2016. aasta olulisematest uuendustest tehnoloogiamaailmas : ekspertidena vastavad Gert Jervan, Argo Virkebau, ... Maarja Kruusmaa jt.]
Pau, Aivar Postimees 2016 / lk. 24-25 : ill

Mikrokontrollerite M68HC11 ja Satt Con 05 riist- ja tarkvara : metoodiline materjal
Tammemäe, Kalle; **Toomsalu, Arvo** 1995 https://www.ester.ee/record=b1069449*est

Mikroprotsessorsüsteemid : kursuseprojekti juhendmaterjal
Toomsalu, Arvo 1998 https://www.ester.ee/record=b1061287*est

Mikroprotsessorsüsteemid : kursuseprojekti metoodiline juhend
Toomsalu, Arvo 1996 https://www.ester.ee/record=b1619347*est

Miniaturized wireless monitor for long-term monitoring of newborns
Leier, Mairo; **Jervan, Gert** BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 193-196 : ill

Mining and modelling web user engagement : a survey on academic sites for framework establishment [Electronic resource]
Robal, Tarmo; **Kalja, Ahto** PICMET '16 : Portland International Conference on Management of Engineering and Technology : proceedings. Technology Management for Social Innovation 2016 / p. 1942-1952 : ill. [USB] https://doi.org/10.1109/PICMET.2016.7806759

A model for users' action prediction based on locality profiles
Robal, Tarmo; **Kalja, Ahto** Information systems development : challenges in practice, theory and education. Volume 1 2009 / p. 169-182 https://link.springer.com/chapter/10.1007/978-0-387-68772-8_14

Modeling sequential circuits with shared structurally synthesized BDDs
Ubar, Raimund-Johannes; **Marenkov, Mihhail**; **Mironov, Dmitri**; **Viies, Vladimir** Proceedings of 2014 9th International Design & Test Symposium (IDT) : Sheraton Club des Pins Hotel, Algiers, Algeria, December 16-18, 2014 2014 / p. 130-135 : ill

Modelling of multirate multivariable control systems : a state-space approach : thesis submitted to Tallinn Technical University in candidature for the degree of Doctor of Philosophy in Engineering
Astrov, Igor 2000 http://www.ester.ee/record=b1707861*est

A modular 6LoWPAN-based wireless sensor body area network for health-monitoring applications
Le Moullec, Yannick; **Lecat, Yoann**; **Annus, Paul**; **Land, Raul**; **Kuusik, Alar**; **Reidla, Marko**; **Hollstein, Thomas**; **Reinsalu, Uljana**; **Tammemäe, Kalle**; **Ruberg, Priit** APSIPA ASC 2014 : Asia-Pacific Signal and Information Processing Association Annual Summit and Conference 2014 : December 9-12, 2014, Siem Reap, city of Angkor Wat, Cambodia 2014 / [4] p. : ill

Morphable compression architecture for efficient configuration in CGRAs
Jafri, Syed Mohammad Asad Hassan; Tajammul, Muhammad Adeel; **Ellervee, Peeter** 2014 17th Euromicro Conference on Digital System Design : DSD 2014 : 27-29 August 2014, Verona, Italy : proceedings 2014 / p. 42-49 : ill

Motivation-driven learning processes at the example of embedded systems
Hollstein, Thomas; **Reinsalu, Uljana**; **Leier, Mairo** 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 3-6 : ill

A multilevel modelling environment for machine elements design
Kalja, Ahto; **Kindel, Kristiina**; **Tiidemann, Mart**; **Tiidemann, Tiit** OST-01 Symposium on Machine Design : Tallinn, Estonia, October 4-5, 2001 : proceedings 2001 / p. 45-50 : ill https://www.ester.ee/record=b1642353*est

Multiple control fault testing in digital systems with high-level decision diagrams
Ubar, Raimund-Johannes; **Oyeniran, Adeboye Stephen** 2016 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 20th edition : 19th-21st May, Cluj-Napoca, Romania : proceedings 2016 / [6] p. : ill http://dx.doi.org/10.1109/AQTR.2016.7501287

Multiple fault testing in systems-on-chip with high-level decision diagrams
Ubar, Raimund-Johannes; **Oyeniran, Adeboye Stephen**; Schölzel, Mario; Vierhaus, Heinrich Theodor Proceedings of 2015 10th International Design & Test Symposium (IDT) : Dead Sea, Jordan, 14-16 December 2015 2015 / p. 66-71 : ill http://dx.doi.org/10.1109/IDT.2015.7396738

Mutation-based verification and error correction in high-level designs = Mutatsioonidel põhinev verifitseerimine ja vigade parandamine kõrgtaseme skeemides
Hantson, Hanno 2015 https://www.ester.ee/record=b4518212*est

Muuk - esimesed triibulised
Tammemäe, Kalle Mente et Manu 2014 / lk. 7-9 : ill https://artiklid.elnet.ee/record=b2679161*est

Nanoelectronics aging mitigation using SSBDD based techniques and dedicated sensors
Ubar, Raimund-Johannes; Vargas, Fabian; **Jenihhin, Maksim**; **Raik, Jaan** MEDIAN Workshop on Circuit Reliability : Modeling and Monitoring, Rome, Italy, February 25, 2013 2013 / [1] p

New built-in self-test scheme for SoC interconnect
Jutman, Artur; **Ubar, Raimund-Johannes**; **Raik, Jaan** The 9th World Multi-Conference on Systemics, Cybernetics and Informatics : WMSCI 2005 : July 10-13, 2005, Orlando, Florida, USA. Vol. IV 2005 / p. 19-24 : ill https://www.researchgate.net/publication/237375234_New_Built-In_Self-Test_Scheme_for_SoC_Interconnect

New fault models and self-test generation for microprocessors using High-Level Decision Diagrams
Jasnetski, Artjom; **Raik, Jaan**; **Tšertov, Anton**; **Ubar, Raimund-Johannes** 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 251-254 : ill

New generations of Estonian eGovernment components
Kalja, Ahto; **Robal, Tarmo**; Vallner, Uuno PICMET '15 : proceedings : Management of the Technology Age 2015 / p. 625-631 : ill http://dx.doi.org/10.1109/PICMET.2015.7273002

New generations of Estonian eGovernment components
Kalja, Ahto; **Robal, Tarmo**; Vallner, Uuno PICMET '15 Conference : Management of the Technology Age : August 2-6, 2015, Portland, Oregon, USA : conference bulletin 2015 / p. 93

A new measure for calculating multiple fault coverage of microprocessor self-test
Oyeniran, Adeboye Stephen; **Odozi, Uzochukwu Eddie**; **Ubar, Raimund-Johannes** BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill http://www.ester.ee/record=b2150914*est

NOC mapping and scheduling
Nikiforov, Deniss Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 73-78 : ill

NoCDepend : a flexible and scalable dependability technique for 3D networks-on-chip
Hollstein, Thomas; **Azad, Siavoosh Payandeh**; **Kogge, Thilo**; Ying, Haoyuan; Hofmann, Klaus 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 75-78 : ill http://dx.doi.org/10.1109/DDECS.2015.30

A novel random approach to diagnostic test generation
Osimiry, Emmanuel Ovie; **Ubar, Raimund-Johannes**; **Kostin, Sergei**; **Raik, Jaan** 2nd IEEE NORCAS Conference : 1-2 November 2016, Copenhagen, Denmark 2016 / [4] p. : ill https://doi.org/10.1109/NORCHIP.2016.7792915

Off-line testing of crosstalk induced glitch faults in NoC Interconnects
Bengtsson, Tomas; Kumar, Shashi; **Jutman, Artur**; **Ubar, Raimund-Johannes** Proceedings [of] 24th IEEE Norchip Conference : Linköping, Sweden, 20-21 November 2006 2006 / p. 221-225 : ill http://dx.doi.org/10.1109/NORCHP.2006.329215

Off-line testing of delay faults in NoC interconnects
Bengtsson, Tomas; **Jutman, Artur**; Kumar, Shashi; Peng, Zebo; **Ubar, Raimund-Johannes** 9th EUROMICRO Conference on Digital Systems Design : Architectures, Methods and Tools (DSD 2006) : 30 August 2006-1 September 2006, Cavtat near Dubrovnik, Croatia : proceedings 2006 / p. 677-680 : ill http://dx.doi.org/10.1109/DSD.2006.72

On automatic software-based self-test program generation based on high-Level decision diagrams
Jasnetski, Artjom; **Ubar, Raimund-Johannes**; **Tšertov, Anton** LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguacu, Brazil, 6th-9th April 2016 2016 / p. 177 http://dx.doi.org/10.1109/LATW.2016.7483357

On coverage of timing related faults at board level
Jutman, Artur; **Aleksejev, Igor**; **Devadze, Sergei** 2016 21st IEEE European Test Symposium (ETS) : May 23rd-26th 2016, Amsterdam, The Netherlands : proceedings 2016 / [2] p. : ill https://doi.org/10.1109/ETS.2016.7519295

On in-system programming of non-volatile memories
Tšertov, Anton; **Devadze, Sergei**; **Jutman, Artur**; **Jasnetski, Artjom** International journal of microelectronics and computer science 2013 / p. 72-78 : ill

On in-system programming of non-volatile memories
Tšertov, Anton; **Devadze, Sergei**; **Jutman, Artur**; **Jasnetski, Artjom** Proceedings of the 20th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2013, Gdynia, Poland, June 20-22, 2013 2013 / p. 408-413 : ill

On integration of object-oriented applications with relational databases
Astrova, Irina 2003 http://www.ester.ee/record=b1833107*est

On proving the concept of an ontology aided software refactoring tool
Põld, Janari; **Robal, Tarmo**; **Kalja, Ahto** Databases and information systems VII : selected papers from the tenth International Baltic Conference, DB&IS 2012 2013 / p. 84-94 https://doi.org/10.3233/978-1-61499-161-8-84 Article collection metrics at Scopus Article at Scopus Article at WOS

On reusability of verification assertions for testing
Jenihhin, Maksim; **Raik, Jaan**; **Ubar, Raimund-Johannes**; **Tšepurov, Anton** BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 151-154 : ill

On using genetic algorithm for test generation
Brik, Marina; **Raik, Jaan**; **Ubar, Raimund-Johannes**; **Ivask, Eero** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics

Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 233-236 : ill

On-line fault classification and handling in IEEE1687 based fault management system for complex SoCs
Shibin, Konstantin; **Devadze, Sergei**; **Jutman, Artur** LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguacu, Brazil, 6th-9th April 2016 2016 / p. 69-74 : ill https://doi.org/10.1109/LATW.2016.7483342

On-line monitoring of dialysis adequacy using diasens optical sensor: accurate Kt/V estimation by smoothing algorithms
Talisainen, Aleksei; **Kostin, Sergei**; **Karai, Deniss**; **Fridolin, Ivo**; **Ubar, Raimund-Johannes** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 273-276 : ill

Ontology-based customization of a scheduling system for discrete manufacturing
Sanko, Jelena; **Haav, Hele-Mai**; **Kotkas, Vahur** Databases and information systems IX : selected papers from the twelfth International Baltic Conference, DB&IS 2016 2016 / p. 57-70 : ill https://doi.org/10.3233/978-1-61499-714-6-57 Conference Proceedings at Scopus Article at Scopus Article at WOS

Open source on-chip logic analyzer for FPGA-s
Ehrenpreis, Lauri; **Ellervee, Peeter**; **Tammemäe, Kalle** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 99-102 : ill

Optimization methodologies for Cycle-Accurate SystemC models converted from RTL VHDL
Saif Abrar, Syed; **Jenihhin, Maksim**; **Raik, Jaan** IP-SoC 2013 : IP embbeded system conference and exhibition : Grenoble, France, November 6-7, 2013 2013

Optimization of address-based data sorting unit with external memory support
Mihhailov, Dmitri; **Rjabov, Artjom**; Sklyarov, Valery; Skliarova, Iouliia; **Sudnitsõn, Aleksander** CompSysTech'13 : proceedings of the 14th International Conference on Computer Systems and Technologies 2013 / p. 83-90 : ill https://doi.org/10.1145/2516775.2516807 Conference Proceedings at Scopus Article at Scopus

Optimization of boundary scan tests using FPGA-based efficient scan architectures
Aleksejev, Igor; **Devadze, Sergei**; **Jutman, Artur**; **Shibin, Konstantin** Journal of electronic testing : theory and applications (JETTA) 2016 / p. 245-255 : ill https://doi.org/10.1007/s10836-016-5588-y Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Optimization of built-in self-test in digital systems = Sisseehitatud enesetestimise optimeerimine digitaalsüsteemides
Kruus, Helena 2011

Optimization of FPGA-based circuits for recursive data sorting
Mihhailov, Dmitri; Sklyarov, Valery; Skliarova, Iouliia; **Sudnitsõn, Aleksander** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 129-132 : ill

Optimization of FSMs network by new encoding strategy
Fomina, Jelena; **Sudnitsõn, Aleksander**; Vasiliev, Roman BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 119-122 : ill

Optimization of multisine excitation for a bioimpedance measurement device
Ojarand, Jaan; **Annus, Paul**; **Min, Mart**; **Gorev, Maksim**; **Ellervee, Peeter** I2MTC 2014 IEEE International Instrumentation and Measurement Technology Conference : Instrumentation and Measurement for Sustainable Development : Radisson Montevideo Victoria Plaza Hotel & Conference Center, May 12-15, 2014, Montevideo, Uruguay : proceedings 2014 / p. 829-832 : ill https://doi.org/10.1109/I2MTC.2014.6860859 Conference proceedings at Scopus Article at Scopus Article at WOS

Optimization of the store-and-generate based built-in self-test
Ubar, Raimund-Johannes; **Jervan, Gert**; **Kruus, Helena**; **Orasson, Elmet**; **Aleksejev, Igor** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 199-202 : ill

Otstarbeka, õiglase ja tõhusa Eesti suunas
Ubar, Raimund-Johannes Insenerikultuur Eestis. 2 1995 / lk. 179-185 https://www.ester.ee/record=b1063622*est

Overview about low-level and high-level decision diagrams for diagnostic modeling of digital systems
Ubar, Raimund-Johannes Facta Universitatis [Niš]. Series electronics and energetics 2011 / p. 303-324 : ill http://dx.doi.org/10.2298/FUEE1103303U

Perceptions of software development practitioners on client learning

Ojastu, Deniss; **Robal, Tarmo**; **Kalja, Ahto** Databases and Information Systems : proceedings of the 11th International Baltic Conference, Baltic DB&IS 2014 : Tallinn, Estonia, 8-11 June, 2014 2014 / p. 397-406

Performance analysis of cosimulating processor core in VHDL and SystemC
Saif Abrar, Syed; Shyam Kiran A.; **Jenihhin, Maksim**; **Raik, Jaan**; Babu, C. Proceedings of the 2013 International Conference on Advances in Computing, Communications and Informatics (ICACCI) : 22–25 August 2013, Mysore, India 2013 / p. 563-568 : ill

Pildikesi poolest sajandist : arvutitehnika instituudi lugu
Ubar, Raimund-Johannes 2016 http://www.ester.ee/record=b4639382*est

Pipelined execution of data-parallel algorithms
Gorev, Maksim; **Ubar, Raimund-Johannes** BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 109-112 : ill

Polymorphic configuration architecture for CGRAs
Jafri, Syed Mohammad Asad Hassan; **Tajammul, Muhammad Adeel**; Hermani, Ahmed; Paul, Kolin; Plosila, Juha; **Ellervee, Peeter**; Tenhunen, Hannu IEEE transactions on Very Large Scale Integration (VLSI) Systems 2016 / p. 403-407 : ill
http://dx.doi.org/10.1109/TVLSI.2015.2402392

Practical works for on-line teaching design and test of digital circuits
Jutman, Artur; **Ubar, Raimund-Johannes**; Hahanov, V.; Skvortsova, O. The 9th IEEE International Conference on Electronics, Circuits and Systems : ICECS 2002 : September 15-18, 2002, Dubrovnik, Croatia. Volume III 2002 / p. 1223-1226 : ill
http://dx.doi.org/10.1109/ICECS.2002.1046474

Practicing start-up culture in teaching embedded systems
Reinsalu, Uljana; **Azad, Siavoosh Payandeh**; **Leier, Mairo**; **Tammemäe, Kalle**; **Hollstein, Thomas** EWME 2016 : 11th European Workshop on Microelectronics Education : May 11-13, 2016, Southampton, UK 2016 / [6] p. : ill
https://doi.org/10.1109/EWME.2016.7496463

Preface
Ubar, Raimund-Johannes; **Raik, Jaan**; Vierhaus, Heinrich Theodor Design and test technology for dependable systems-on-chip 2011 / p. xxii-xxviii

Preface
Haav, Hele-Mai; **Kalja, Ahto**; **Robal, Tarmo** Databases and information systems VIII : selected papers from the Eleventh International Baltic Conference, DB&IS 2014 2014 / p. v

Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia
2012 http://www.ester.ee/record=b2777270*est

Processing N-ary trees in reconfigurable hardware
Sklyarov, Valery; **Skliarova, Iouliia**; **Sudnitsõn, Aleksander** 2013 25th International Conference on Microelectronics (ICM) : 15–18 December 2013, Beirut-Lebanon 2013 / p. 13-16 : ill

Processing sorted subsets in a multi-level reconfigurable computing system
Rjabov, Artjom; Sklyarov, Valery; Skliarova, Iouliia; **Sudnitsõn, Aleksander** Elektronika ir elektrotechnika = Electronics and electrical engineering 2015 / p. 30-33 : ill https://doi.org/10.5755/j01.eee.21.2.11509 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Professor Andres Keevallik juhib Eesti parima arengudünaamikaga kõrgkooli
Keevallik, Andres; Ehavere, Liis Rapla inimesed 2016 / lk. 146-148 : ill

Professor Raimund Ubari ettekanne [audoktorite promotsioonil TTÜ Nõukogu pidulikul istungil 1. sept. 1993]
Ubar, Raimund-Johannes 75 aastat Tallinna Tehnikaülikooli 1994 / lk. 106-109 https://www.ester.ee/record=b1066846*est

Programmeerimisvõistlus IEEEXtreme 9.0 24h
Tammemäe, Kalle Mente et Manu 2015 / lk. 8-9 : fot https://artiklid.elnet.ee/record=b2750867*est

A proposal for optimisation of low-powered FSM testing
Brik, Marina; **Fomina, Jelena**; **Ubar, Raimund-Johannes** Proceedings of IEEE East-West Design & Test Workshop (EWDTW'05) : Odessa, Ukraine, September 15-19, 2005 2005 / p. 15-20

Pulse wave registration from radial artery using photoplethysmographic method
Pilt, Kristjan; **Leier, Mairo**; **Silluta, Sandra**; **Kööts, Kristina**; **Meigas, Kalju**; **Viigimaa, Margus** Conference proceedings : 37th

Annual International Conference of the IEEE Engineering in Medicine and Biology Society : Milan, Italy, August 25-29 2015 2015 / p. 6425-6428 : ill https://doi.org/10.1109/EMBC.2015.7319863 Conference Proceedings at Scopus Article at Scopus Article at WOS

Rahvusvahelise inseneriorganisatsiooni IEEE Eesti sektsioon sai 10-aastaseks
Tammemäe, Kalle Mente et Manu 2016 / lk. 40-41 : fot http://www.ttu.ee/public/u/ulikool/Tutvustus/ajaleht-mente-et-manu/MM_2016_05/index.html https://artiklid.elnet.ee/record=b2797145*est

Raimund Ubari lühisõnavõtt : riigi teadus-, kultuuri- ja spordipreemiate ning F.J.Wiedemanni keeleauhinna kätteandmisel 24. veebruaril 2016. aastal
Ubar, Raimund-Johannes Raimund-Johannes Ubar. Bibliograafia 2016 / lk. 45-46

Reconfigurable data acquisition unit for bioimpedance measurements
Pesonen, Vadim; **Gorev, Maksim**; **Annus, Paul**; **Min, Mart**; **Ellervee, Peeter** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 257-260 : ill

Refactoring - key to success for constantly developed projects [Electronic resource]
Põld, Janari; **Kalja, Ahto**; **Robal, Tarmo** Proceedings of the 26th International Conference on Information Modelling and Knowledge Bases - EJC 2016 : June 6-10, 2016, Tampere, Finland 2016 / p. 15-24. [USB]

Register-transfer level deductive fault simulation using decision diagrams
Reinsalu, Uljana; **Raik, Jaan**; **Ubar, Raimund-Johannes** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 193-196 : ill

Rejuvenation of nanoscale logic at NBTI-critical paths using evolutionary TPG
Palermo, N.; **Tihhomirov, Valentin**; Copetti, Thiago; **Jenihhin, Maksim**; **Raik, Jaan**; **Kostin, Sergei** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill http://dx.doi.org/10.1109/LATW.2015.7102405

Rejuvenation of NBTI-impacted processors using evolutionary generation of assembler programs
Pellerey, Francesco; **Jenihhin, Maksim**; Squillero, Giovanni; **Raik, Jaan**; Sonza Reorda, Matteo; **Tihhomirov, Valentin**; **Ubar, Raimund-Johannes** 2016 IEEE 25th Asian Test Symposium : 21-24 November 2016, Hiroshima, Japan 2016 / p. 304-309 : ill https://doi.org/10.1109/ATS.2016.57 Conference Proceedings at Scopus Article at Scopus Article at WOS

Reliability continuum and academic EDA
Jenihhin, Maksim 2nd International Training School on Manufacturable and Dependable Multicore Architectures at Nanoscale (MEDIAN ISTS 2015) : Prague, Czech Republic, July 13-15, 2015 2015 / [1] p

Reliable health monitoring and fault management infrastructure based on embedded instrumentation and IEEE 1687
Jutman, Artur; **Shibin, Konstantin**; **Devadze, Sergei** IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 240-249 : ill https://doi.org/10.1109/AUTEST.2016.7589605

Remote and virtual laboratories in problem-based learning scenarios
Wuttke, Heinz-Dietrich; **Ubar, Raimund-Johannes**; Henke, Karsten 2010 IEEE International Symposium on Multimedia ISM 2010 : 13-15 December 2010, Taichung, Taiwan : proceedings 2010 / p. 377-382 : ill http://dx.doi.org/10.1109/ISM.2010.63

Requirements-driven model-based testing of the IP Multimedia Subsystem
Ernits, Juhan-Peep; **Kääramees, Marko**; Raiend, Kullo; Kull, Andres BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 203-206 : ill

Research and training environment for digital design and test
Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 34th ASEE/IEEE Frontiers in Education Conference : October 20-23, 2004, Savannah, GA 2004 / p. S3F-18-S3F-23 : ill http://dx.doi.org/10.1109/FIE.2004.1408779

Research in digital design and test at Tallinn University of Technology
Ubar, Raimund-Johannes; **Jervan, Gert**; **Jutman, Artur**; **Raik, Jaan**; **Ellervee, Peeter**; **Kruus, Margus** Radioelectronics & informatics 2008 / p. 4-12 : ill http://www.ewdtest.com/ri/%E2%84%96-1-40-january-march-2008/

Reseeding using compaction of pre-generated LFSR sub-sequences
Jutman, Artur; **Aleksejev, Igor**; **Raik, Jaan**; **Ubar, Raimund-Johannes** ICECS 2008 : The 15th IEEE International Conference on Electronics, Circuits and Systems : Malta 2008 / p. 1290-1295 : ill http://dx.doi.org/10.1109/ICECS.2008.4675096

Respiration signal extraction from photoplethysmogram using pulse wave amplitude variation
Leier, Mairo; **Jervan, Gert**; Stork, Wilhelm 2014 IEEE International Conference on Communications (ICC) : Sydney, Australia, June

10-14, 2014 2014 / p. 3535-3540 : ill

Riistvara kirjeldamiskeel - VHDL : metoodiline materjal
Tammemäe, Kalle 2003 http://www.ester.ee/record=b1605950*est

Riistvara kirjeldamiskeel VHDL : metoodiline materjal
Tammemäe, Kalle 2002 http://www.ester.ee/record=b1605950*est

Runtime contention and bandwidth-aware adaptive routing selection strategies for networks-on-chip
Samman, Faizal; **Hollstein, Thomas**; Glesner, Manfred IEEE transactions on parallel and distributed systems 2013 / p. 1411-1421 : ill https://doi.org/10.1109/TPDS.2012.200 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Run-time reconfigurable instruments for advanced board-level testing
Aleksejev, Igor; **Jutman, Artur**; **Devadze, Sergei** IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 385-392 : ill https://doi.org/10.1109/AUTEST.2016.7589627

Scalable algorithm for structural fault collapsing in digital circuits
Ubar, Raimund-Johannes; **Jürimägi, Lembit**; **Orasson, Elmet**; **Raik, Jaan** 2015 IFIP/IEEE International Conference on Very Large Scale Integration (VLSI-SoC) : October 5-7, 2015, Daejeon, Korea 2015 / p. 171-176 : ill

Scalable open platform for reliable medical sensorics = Laiendatav avatud platvorm usaldusväärsete meditsiiniliste sensorite jaoks
Leier, Mairo 2016 https://www.ester.ee/record=b4575148*est

Second IEEE East-West Design and Test Workshop
Hahanov, Vladimir; **Ubar, Raimund-Johannes** IEEE journal of design & test of computers 2004 / p. 594

Selected issues of modeling, verification and testing of digital systems
Jutman, Artur 2004 https://www.ester.ee/record=b1989760*est

Self-diagnosis in digital systems = Isediagnoosivad digitaalsüsteemid
Kostin, Sergei 2012 https://www.ester.ee/record=b2757857*est

Self-learning tool for digital test
Ubar, Raimund-Johannes; **Orasson, Elmet**; **Evartson, Teet** Proceedings of 2nd International Conference "Distance Learning - Educational Sphere of the XXI Century" 2002 / p. 36-38 : ill

Self-testing of pipe-lined signal processing architectures at-speed
Gorev, Maksim; **Ubar, Raimund-Johannes**; **Ellervee, Peeter** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 25-28 : ill

Service quality meter design for self-aware systems
Tammemäe, Kalle; **Leier, Mairo** AmiES-2015 : Ambient Intelligence and Embedded Systems : International Symposium, 24-26 September, 2015, Oostende, Belgium 2015 / [4] p. : ill

7-valued algebra for transition delay fault analysis
Kõusaar, Jaak; **Ubar, Raimund-Johannes** BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 89-92 : ill

Shared Structurally Synthesized BDDs for speeding-up parallel pattern simulation in digital circuits
Ubar, Raimund-Johannes; **Jürimägi, Lembit**; **Raik, Jaan** 2015 Nordic Circuits and Systems Conference (NORCAS) : NORCHIP & International Symposium on System-on-Chip (SoC) : 1st IEEE NORCAS Conference : 26-28 October 2015, Oslo, Norway 2015 / [4] p. : ill http://dx.doi.org/10.1109/NORCHIP.2015.7364406

Simulation of digital systems with high-level decision diagrams
Morawiec, Adam; **Raik, Jaan**; **Ubar, Raimund-Johannes** The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 35-38 : ill

Simulation-based hardware verification with high-level decision diagrams = Simuleerimisel põhinev riistvara verifitseerimine kõrgtaseme otsustusdiagrammidel
Jenihhin, Maksim 2008 https://www.ester.ee/record=b2431332*est

Simulation-based verification with APRICOT framework using high-level decision diagrams
Jenihhin, Maksim; **Raik, Jaan**; **Tšepurov, Anton**; **Ubar, Raimund-Johannes** East-West Design & Test Symposium : Moscow, September 18-21, 2009 2009 / p. 13-16 : ill

Sissejuhatus füüsikasse
Lorents, Peeter 1998 http://www.ester.ee/record=b1207605*est

Sleep apnea pre-screening on neonates and children with shoe integrated sensors [Electronic resource]
Leier, Mairo; **Jervan, Gert** 31st Norchip Conference : Vilnius, Lithuania, 11-12 November 2013 : conference program and papers 2013 / [4] p. : ill [USB]

A small-size sleep apnea pre-screening prototype for neonates and children
Leier, Mairo; **Jervan, Gert** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 49-52 : ill

Smart photoplethysmographic sensor for pulse wave registration at different vascular depths
Leier, Mairo; **Jervan, Gert**; **Pilt, Kristjan** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 67-70 : ill

Smart photoplethysmographic sensor for pulse wave registration at different vascular depths
Leier, Mairo; **Pilt, Kristjan**; **Karai, Deniss**; **Jervan, Gert** Conference proceedings : 37th Annual International Conference of the IEEE Engineering in Medicine and Biology Society : Milan, Italy, August 25-29 2015 2015 / p. 1849-1852 : ill https://doi.org/10.1109/EMBC.2015.7318741 Conference Proceedings at Scopus Article at Scopus Article at WOS

Smart, wireless modular communication platform
Ruberg, Priit; **Hollstein, Thomas**; **Reinsalu, Uljana**; **Tammemäe, Kalle**; **Le Moullec, Yannick**; **Kuusik, Alar**; **Reidla, Marko**; **Annus, Paul** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 111-112 : ill

SoCDep2 : a framework for dependable task deployment on many-core systems under mixed-criticality constraints
Azad, Siavoosh Payandeh; **Niazmand, Behrad**; **Ellervee, Peeter**; **Raik, Jaan**; **Jervan, Gert**; **Hollstein, Thomas** 2016 11th International Symposium on Reconfigurable Communication▮centric Systems▮on▮Chip (ReCoSoC) : June 27▮29, 2016, Tallinn, Estonia 2016 / [6] p. : ill https://doi.org/10.1109/ReCoSoC.2016.7533903

Software-based self-test generation for microprocessors with high-level decision diagrams
Ubar, Raimund-Johannes; **Tšertov, Anton**; **Jasnetski, Artjom**; **Brik, Marina** LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

Software-based self-test generation for microprocessors with high-level decision diagrams
Jasnetski, Artjom; **Ubar, Raimund-Johannes**; **Tšertov, Anton**; **Brik, Marina** Proceedings of the Estonian Academy of Sciences 2014 / p. 48-61 : ill https://artiklid.elnet.ee/record=b2665215*est https://doi.org/10.3176/proc.2014.1.08 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Solving computationally intensive problems in reconfigurable hardware : a case study
Skliarova, Iouliia; Vallejo, Tiago; Sklyarov, Valery; **Sudnitsõn, Aleksander**; **Kruus, Margus** Journal of convergence information technology (JCIT) : an international journal 2013 / p. 601-609 : ill

SPICE-inspired fast gate-level computation of NBTI-induced delays in nanoscale logic
Kostin, Sergei; **Raik, Jaan**; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim** 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 223-228 : ill

SSBDDs : advantageous model and efficient algorithms for digital circuit modeling, simulation & test
Jutman, Artur; **Raik, Jaan**; **Ubar, Raimund-Johannes** 5th International Workshop on Boolean Problems : September 19-20, 2002,Freiberg (Sachsen) : proceedings 2002 / p. 157-166 : ill

Structurally synthesized multiple input BDDs for simulation of digital circuits
Ubar, Raimund-Johannes; **Mironov, Dmitri**; **Raik, Jaan**; **Jutman, Artur** 16th IEEE International Conference on Electronics, Circuits, and Systems, ICECS 2009 : Yasmine Hammamet, Tunesia, 13-19 December, 2009 2009 / p. 451-454 : ill http://dx.doi.org/10.1109/ICECS.2009.5410895

A study on effective knowledge reuse in multi-platform web applications user interfaces
Marenkov, Jevgeni; **Robal, Tarmo**; **Kalja, Ahto** PICMET '15 Conference : Management of the Technology Age : August 2-6, 2015, Portland, Oregon, USA : conference bulletin 2015 / p. 68

A study on effective knowledge reuse in multi-platform web applications user interfaces
Marenkov, Jevgeni; **Robal, Tarmo**; **Kalja, Ahto** PICMET '15 : proceedings : Management of the Technology Age 2015 / p. 1351-1361 : ill https://doi.org/10.1109/PICMET.2015.7273083

A study on immediate automatic usability evaluation of web application user interfaces
Marenkov, Jevgeni; **Robal, Tarmo**; **Kalja, Ahto** Databases and Information Systems : 12th International Baltic Conference, DB&IS 2016, Riga, Latvia, July 4-6, 2016 : proceedings 2016 / p. 257-271 : ill https://doi.org/10.1007/978-3-319-40180-5_18 Conference Proceedings at Scopus Article at Scopus Article at WOS

A study on user click behaviour for WIS user interface improvements
Marenkov, Jevgeni; **Robal, Tarmo**; **Kalja, Ahto** Databases and information systems VIII : selected papers from the Eleventh International Baltic Conference, DB&IS 2014 2014 / p. 173-186 : ill https://doi.org/10.3233/978-1-61499-458-9-173 Conference proceedings at Scopus Article at Scopus Article at WOS

Studying the incorrect user behaviour in sophisticated self-service portal user interfaces
Marenkov, Jevgeni; **Robal, Tarmo**; **Kalja, Ahto** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 71-74 : ill

A suite of IEEE 1687 benchmark networks
Tšertov, Anton; **Jutman, Artur**; **Devadze, Sergei** 2016 IEEE International Test Conference (ITC) : proceedings 2016 / art. 6.1, p. 1-10 : ill https://doi.org/10.1109/TEST.2016.7805840

Süsteemse käsitluse alused : [loengukonspekt]
Lorents, Peeter 2004 http://www.ester.ee/record=b2871388*est

Süsteemse käsitluse alused : riigikaitse ja julgeoleku põhiküsimused
Lorents, Peeter 1998 https://www.ester.ee/record=b1054840*est

Synchronization, calibration and triggering of IEEE 1687 embedded instruments
Jutman, Artur; **Devadze, Sergei**; **Shibin, Konstantin** The Seventeenth Workshop on RTL and High Level Testing (WRTLT'16) : November 24-25, 2016, Aki Grand Hotel, Hiroshima, Japan 2016 / [6] p

Synthesis of high-level decision diagrams for functional test pattern generation
Ubar, Raimund-Johannes; **Raik, Jaan**; **Karputkin, Anton**; **Tombak, Mati** Proceedings of the 16th International Conference Mixed Design of Integrated Circuits and Systems MIXDES 2009 : Lodz, Poland, 25-27 June, 2009 2009 / p. 519-524 : ill

Synthesis of multiple fault oriented test groups from single fault test sets [Electronic resource]
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Raik, Jaan** 2013 8th International Conference on Design & Technology of Integrated Systems in Nanoscale Era (DTIS) : 26-28 March 2013, Abu Dhabi, UAE 2013 / p. 36-41 : ill [CD-ROM]

A synthesis-agnostic behavioral fault model for high gate-level fault coverage
Karputkin, Anton; **Raik, Jaan** 2016 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2016 / p. 1124-1127 : ill https://ieeexplore.ieee.org/document/7459477/figures#figures

SysML in systems engineering course
Kruus, Helena; **Robal, Tarmo**; **Jervan, Gert** 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 177-181 : ill

A system for teaching basic and advanced topics of IEEE 1149.1 boundary scan standard (extended abstract)
Jutman, Artur; Rosin, Vjatšeslav; **Sudnitsõn, Aleksander**; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich Proceedings of 16th EAEEIE Conference on Innovation in Education for Electrical and Information Engineering (EIE) : Lappeenranta, Finland, 6th-8th June 2005 2005 / [2] p. : ill

System modeling for processor-centric test automation = Süsteemide modelleerimine protsessorikesksete testprogrammide sünteesi automatiseerimiseks
Tšertov, Anton 2012 https://www.ester.ee/record=b2751131*est

SystemC-based loose models : RTL abstraction for design understanding
Abrar, Syed Saif; **Jenihhin, Maksim**; **Raik, Jaan** Workshop on Design Automation for Understanding Hardware Designs DUHDe 2015 : Grenoble, March 13, 2015 2015 / p. 1-6

SystemC-based loose models for simulation speed-up by abstraction of RTL IP cores
Abrar, Syed Saif; **Jenihhin, Maksim**; **Raik, Jaan** 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 71-74 : ill http://dx.doi.org/10.1109/DDECS.2015.39

System-level design of timing-sensitive network-on-chip based dependable systems = Kiipvõrkudel põhinevate ajakriitiliste ja töökindlate süsteemide kõrgtaseme disain
Tagel, Mihkel 2012 https://www.ester.ee/record=b2778263*est

Systems engineering course as a backbone of the computer engineering curricula
Jervan, Gert Proceedings of the 24th International Conference on European Association for Education in Electrical and Information Engineering : 30-31 May 2013, Chania, Greece 2013 / p. 163-166 : ill

zamiaCAD : shall we dance?
Jenihhin, Maksim Open Source Tools for Verification : DVClub 14 January 2013 2013 / 1 p

zamiaCAD : understand, develop and debug hardware designs
Jenihhin, Maksim; **Tihhomirov, Valentin**; **Saif Abrar, Syed**; **Raik, Jaan**; Bartsch, Günter DUHDe : 1st Workshop on Design Automation for Understanding Hardware Designs : March 28, 2014 : Friday Workshop at DATE 2014, Dresden, Germany 2014 / p. 1-6

Zynq-based system for extracting sorted subsets from large data sets
Sklyarov, Valery; Skliarova, Iouliia; **Rjabov, Artjom**; **Sudnitsõn, Aleksander** Journal of microelectronics, electronic components and materials 2015 / p. 142-152 : ill https://ojs.midem-drustvo.si/index.php/InfMIDEM/article/view/117/0 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

A task-oriented design of a biologically inspired underwater robot
Listak, Madis 2007 http://www.ester.ee/record=b2298234*est

Teaching advanced test issues in digital electronics
Ubar, Raimund-Johannes; **Orasson, Elmet**; **Raik, Jaan**; Wuttke, Heinz-Dietrich Proceedings of the 6th IEEE International Conference on Information Technology Based Higher Education and Training : ITHET : July 7-9, 2005, Juan Dolio, Dominican Republic 2005 / p. S2B-1 - S2B-6 : ill http://dx.doi.org/10.1109/ITHET.2005.1560318

Teaching diagnostic modeling of digital systems with decision diagrams [Electronic resource]
Ubar, Raimund-Johannes; **Raik, Jaan**; **Mironov, Dmitri**; **Evartson, Teet**; **Orasson, Elmet**; **Aarna, Margit**; Wuttke, Heinz-Dietrich Proceedings of 12th IASTED International Conference on Computers and Advanced Technology in Education - CATE 2009 : St.Thomas, US, November 22-24, 2009 2009 / p. 1-6. [CD-ROM]

Teaching digital RT-level self-test using a Java applet
Devadze, Sergei; **Jutman, Artur**; **Sudnitsõn, Aleksander**; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich 20th IEEE NORCHIP Conference : Copenhagen, Denmark, November 11-12, 2002 2002 / p. 322-328 : ill

Teaching digital test with BIST analyzer
Jutman, Artur; **Tšertov, Anton**; **Tšepurov, Anton**; **Aleksejev, Igor**; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich 19th EAEEIE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 123-128 : ill http://dx.doi.org/10.1109/EAEEIE.2008.4610171

Teaching FPGA-based systems
Skliarova, Iouliia; Sklyarov, Valery; **Sudnitsõn, Aleksander**; **Kruus, Margus** 2014 IEEE Global Engineering Education Conference (EDUCON) : Istanbul, Turkey, April 2-5, 2014 2014 / p. 460-469 : ill

Teaching modeling in SysML/UML and problems encountered
Kruus, Helena; **Robal, Tarmo**; **Jervan, Gert** Proceedings of the 25th International Conference on European Association for Education in Electrical and Information Engineering : 30 May-June 2014, Cesme, Türkiye 2014 / p. 33-36 : ill

Teaduspreemia laureaadi sõnavõtt : [teaduspreemiate üleandmisel]
Ubar, Raimund-Johannes Eesti Vabariigi preemiad 2016 : teadus. F. J. Wiedemanni keeleauhind. Kultuur. Sport 2016 / lk. 20-21

Teaduspreemia pikaajalise tulemusliku teadus- ja arendustöö eest : Raimund Ubar
Ubar, Raimund-Johannes Eesti Vabariigi preemiad 2016 : teadus. F. J. Wiedemanni keeleauhind. Kultuur. Sport 2016 / lk. 34-61 : fot., portr

Tenniseharrastus Tallinna tehnikaülikoolis. Tennis on au sees : [kommenteerivad Tauno Otto ja Viveeth Govind]
Sulling, Andres; **Otto, Tauno**; **Govind, Vineeth** Mente et Manu 2013 / lk. 26-27 : fot

10th IEEE European Test Symposium
Ubar, Raimund-Johannes; Prinetto, Paolo; **Raik, Jaan** IEEE journal of design & test of computers 2005 / p. 480-481 : phot http://dx.doi.org/10.1109/MDT.2005.106

Test configurations for diagnosing faulty links in NoC switches
Raik, Jaan; **Ubar, Raimund-Johannes**; **Govind, Vineeth** 12th IEEE European Test Symposium ETS 2007 : 20-24 May 2007, Freiburg, Germany : proceedings 2007 / p. 29-34 : ill http://dx.doi.org/10.1109/ETS.2007.41

Test development and deployment tool-set for mixed-signal and digital devices

Mellik, Andres; **Raik, Jaan** BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 163-166 : ill

Testability analysis of digital design verification
Hahanov, V.; Kaminska, M.; **Fomina, Jelena** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 171-174 : ill

The benefits of self-awareness and attention in fog and mist computing
Preden, Jürgo-Sören; **Tammemäe, Kalle**; Jantsch, Axel; **Leier, Mairo**; **Riid, Andri**; Calis, Emine Computer 2015 / p. 37-45 : ill https://doi.org/10.1109/MC.2015.207 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

The most prominent software development concepts cited in IT professionals' blogs
Ojastu, Deniss; **Robal, Tarmo**; **Kalja, Ahto** Perspectives in business informatics research : 14th International Conference, BIR 2015, Tartu, Estonia, August 26-28, 2015 : proceedings 2015 / p. 197-212 https://doi.org/10.1007/978-3-319-21915-8_13 Conference proceedings at Scopus Article at Scopus

The synthesis level in Bloom's taxonomy - a nightmare for an LMS
Wuttke, Heinz-Dietrich; **Ubar, Raimund-Johannes**; Henke, Karsten; **Jutman, Artur** 19th EAEEIE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 199-204 : ill http://dx.doi.org/10.1109/EAEEIE.2008.4610186

3D parallel fault simulation
Gorev, Maksim; **Ubar, Raimund-Johannes** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 39-42 : ill

3D routing model in WSN network
Mosidze, Vakhtang Doctoral School in Information and Communication Technology : proceedings of doctoral session of BEC 2014 : October 6-8 2014, Laulasmaa 2014 / p. 11-14 : ill

Throughput estimation with regard to airtime consumption unfairness in mixed data rate Wi-Fi networks
Abdul-Hadi, Alaa Mohammed; Tarasyuk, Olga; Gorbenko, Anatoliy; Kharchenko, Vyacheslav; **Hollstein, Thomas** Communications - Scientific Letters of the University of Žilina 2014 / p. 84-89 : ill https://komunikacie.uniza.sk/pdfs/csl/2014/01/15.pdf Journal metrics at Scopus Article at Scopus

Tippteadus ja ülikool
Ubar, Raimund-Johannes Mente et Manu 2014 / lk. 11-15 : fot https://artiklid.elnet.ee/record=b2705056*est

Tippteadus ja ülikool
Ubar, Raimund-Johannes Teadusmõte Eestis (VIII). Teaduskultuur : [artiklikogumik] 2013 / lk. 46-53 : portr

A tool for random test generation targeting high diagnostic resolution
Osimiry, Emmanuel Ovie; **Kostin, Sergei**; **Raik, Jaan**; **Ubar, Raimund-Johannes** BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 79-82 : ill http://www.ester.ee/record=b2150914*est

A tool set for teaching design-for-testability of digital circuits
Kostin, Sergei; **Orasson, Elmet**; **Ubar, Raimund-Johannes** EWME 2016 : 11th European Workshop on Microelectronics Education : May 11-13, 2016, Southampton, UK 2016 / [6] p. : ill https://doi.org/10.1109/EWME.2016.7496466

Tools and Techniques for event log analysis
Vaarandi, Risto 2005 https://www.ester.ee/record=b2045293*est

Towards adaptive web - analysing and recommending web users' behaviour = Veebikasutajate käitumise analüüs ja soovitused adaptiivse veebi loomiseks
Robal, Tarmo 2012 https://www.ester.ee/record=b2862251*est

TPI-s kasutatavatest programmidest õppeinfo töötlemisel
Ait, Olev III vabariiklik teaduslik-metoodiline konverents "Õppetöö teaduslik organiseerimine", Kääriku, 24.-25. oktoober 1973. : materjalid 1973 / lk. 128-132 https://www.ester.ee/record=b1324071*est

Transition delay fault simulation with parallel critical path back-tracing and 7-valued algebra
Kõusaar, Jaak; **Ubar, Raimund-Johannes**; **Devadze, Sergei**; **Raik, Jaan** Microprocessors and microsystems 2015 / p. 1130-1138 : ill https://doi.org/10.1016/j.micpro.2015.05.003 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

TransMem : a memory architecture to support dynamic remapping and parallelism in low power high performance CGRAs
Tajammul, Muhammad Adeel; Jafri, Syed Mohammad Asad Hassan; Hemani, Ahmed; **Ellervee, Peeter** 2016 26th International Workshop on Power and Timing Modeling, Optimization and Simulation : PATMOS 2016 : September, 21st to 23th 2016, Bremen, Germany : proceedings 2016 / p. 92-99 : ill https://doi.org/10.1109/PATMOS.2016.7833431

TTBist: a DfT tool for enhancing functional test for SoC
Hermann, K.; **Raik, Jaan**; **Jenihhin, Maksim** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 191-194 : ill

TTÜ doktorant Mairo Leier: "Ma motiveerin iseennast, tehes seda, mis mulle meeldib."
Leier, Mairo Studioosus 2015 / lk. 8-9 https://www.ester.ee/record=b1558644*est

Ultra fast parallel fault analysis on structurally synthesized BDDs
Ubar, Raimund-Johannes; **Devadze, Sergei**; **Raik, Jaan**; **Jutman, Artur** 12th IEEE European Test Symposium ETS 2007 : 20-24 May 2007, Freiburg, Germany : proceedings 2007 / p. 131-136 : ill http://dx.doi.org/10.1109/ETS.2007.43

Untestable fault identification in sequential circuits using model-checking
Raik, Jaan; Fujiwara, Hideo; **Ubar, Raimund-Johannes**; **Krivenko, Anna** Proceedings of the 17th Asian Test Symposium ATS 2008 : November 24-27, 2008, Sapporo, Japan 2008 / p. 21-26 : ill http://dx.doi.org/10.1109/ATS.2008.22

Using mobile technology to enhance teaching reconfigurable systems
Skliarova, Iouliia; Sklyarov, Valery; **Sudnitsõn, Aleksander**; **Kruus, Margus** Proceedings of 2013 IEEE International Conference on Teaching, Assessment and Learning for Engineering (TALE) 2013 / p. 478-483 : ill

Using simulation statistics for bug localization in RTL designs
Tihhomirov, Valentin; **Jenihhin, Maksim**; **Raik, Jaan** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 107-110 : ill

Using Tabu Search for optimization of memory-constrained hybrid BIST
Kruus, Helena; **Jervan, Gert**; **Ubar, Raimund-Johannes** BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 155-158 : ill

Using weighted graphs for fast architecture exploration
Ellervee, Peeter; Klaar, Tarmo; **Kruus, Margus**; **Tammemäe, Kalle** BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 111-114 : ill

Uurimistoetuse juhend ja vormid
Ubar, Raimund-Johannes 1995 https://www.ester.ee/record=b1067614*est

Variable byte-length data compression algorithm
Gorev, Maksim; **Ellervee, Peeter** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 353-356 : ill

Web-based applet for teaching boundary scan standard IEEE 1149.1
Jutman, Artur; **Sudnitsõn, Aleksander**; **Ubar, Raimund-Johannes** Proceedings of the 10th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2003 : Lodz, Poland, 26-28 June 2003 2003 / p. 584-589 : ill
https://www.semanticscholar.org/paper/WEB-BASED-APPLET-FOR-TEACHING-BOUNDARY-SCAN-IEEE-.-J.-Utman/3bd1b47848612e44772b4c84a2913c419de940fa

Web-based framework for distributed remote laboratory in the field of digital system test
Ivask, Eero; **Jutman, Artur**; **Raik, Jaan**; **Ubar, Raimund-Johannes** 19th EAEEIE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 182-187 : ill http://dx.doi.org/10.1109/EAEEIE.2008.4610183

Web-based software package for e-learning and research training in digital system design
Jutman, Artur; **Kruus, Margus**; **Sudnitsõn, Aleksander**; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich Информационные технологии в науке, образовании, телекоммуникации и бизнесе : Материалы XXXII Международной конференции IT+SE'2005 : Украина, Крым, Ялта-Гурзуф, 19-28 мая 2005 г 2005 / [2] p

Web-based tools for finite state machine decomposition with analysis of information flows
Fomina, Jelena; **Keevallik, Andres**; **Kruus, Margus**; **Sudnitsõn, Aleksander** BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 165-168 : ill

Verification and error correction on High-Level Decision Diagrams

Karputkin, Anton 2013

Verification formelle des resultats de la synthese de Haut Niveau : [doktoriväitekiri]
Dušina, Julia 1999

VHDL design debug framework based on zamiaCAD
Tihhomirov, Valentin; **Tšepurov, Anton**; **Saif Abrar, Syed**; **Jenihhin, Maksim**; **Raik, Jaan** DATE 2013 : Design Automation and Test in Europe, March 18-22, 2013, Grenoble, France 2013 / [1] p. : ill

VHDL front-end for high-level synthesis tool xTractor
Ivask, Eero; **Ellervee, Peeter** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 111-114 : ill

Virtual laboratory for research in dependable microelectronics
Diener, Karl-Heinz; Elst, G.; Gramatova, Elena; Kuzmicz, W.; Peng, Z.; **Ubar, Raimund-Johannes** The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 217-220 : ill

Virtual reconfigurable scan-chains on FPGAs for optimized board test
Aleksejev, Igor; **Jutman, Artur**; **Devadze, Sergei**; **Shibin, Konstantin** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill http://dx.doi.org/10.1109/LATW.2015.7102411

Ülikooli ülimaks sihiks on teenida oma rahvast : [kõne rektoriks nimetamisel]
Keevallik, Andres Tehnikaülikool 2000 / 20. märts, lk. 6-7 : portr https://www.ester.ee/record=b5309277*est

X-tee on üks infoühiskonna arendusplaani nurgakividest Eestis [Elektrooniline teavik]
Kalja, Ahto Infotehnoloogia avalikus halduses : aastaraamat 2006 2006 / lk. 26-29 https://www.ester.ee/record=b1696552*est

Декомпозиционный синтез управляющих автоматов на программируемых матрицах и микропроцессорах : диссертация на соискание ученой степени кандидата кандидата технических наук
Sudnitsõn, Aleksander 1983 https://www.ester.ee/record=b4634419*est

Построение тестов для неисправностей комбинационных схем на основе анализа ортогональных дизъюнктивных нормальных форм, представляемых альтернативными графами
Matrosova, A.Yu.; Pleshkov, A.G.; **Ubar, Raimund-Johannes** Автоматика и телемеханика 2005 / с. 158-174 : ил http://mi.mathnet.ru/at1333

Применение ЭВМ ЕС-1020 при выполнении лабораторных работ по курсу "Физика горных пород. Горное давление"
Kripsaar, Ervin; **Zelimhanova, Larissa** Опыт применения технических средств в учебном процессе : тезисы докладов VI зональной научно-методической конференции преподавателей вузов республик Прибалтики, БССР и Калининградской области РСФСР 1986 / с. 178-179 https://www.ester.ee/record=b2856606*est

Раймунд Убар: ученые делают свое дело, политики - свое : [интервью с Р. Убаром]
Ubar, Raimund-Johannes Босс : бизнес, организаця, стратегия, системы 2012 / с. 57-58 : ил